

# Exploiting defects for luminescent materials investigation

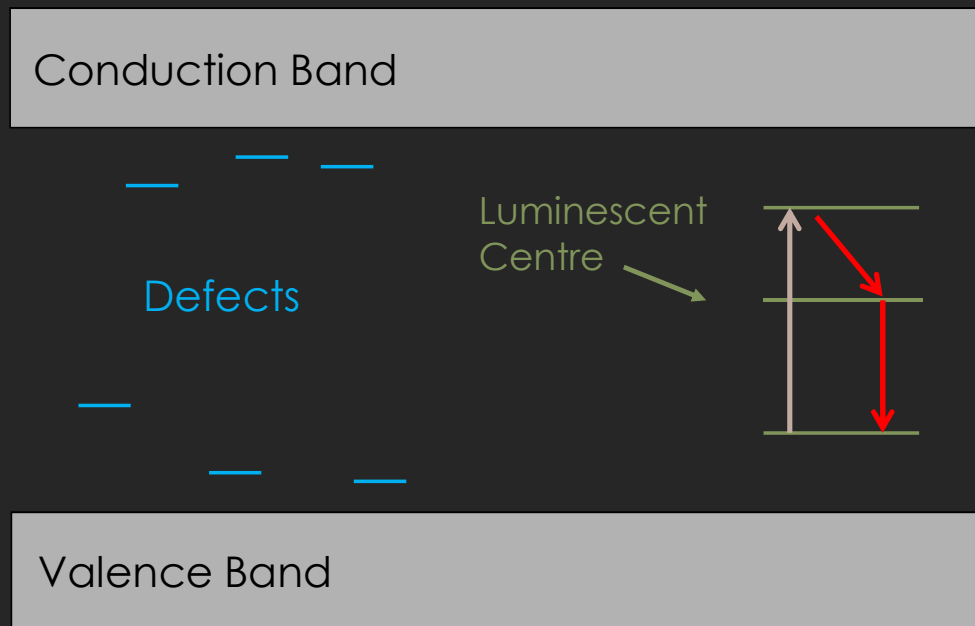
Mauro Fasoli

University of Milano-Bicocca



# Laser vs. scintillation mechanism

Critical defects are application dependent



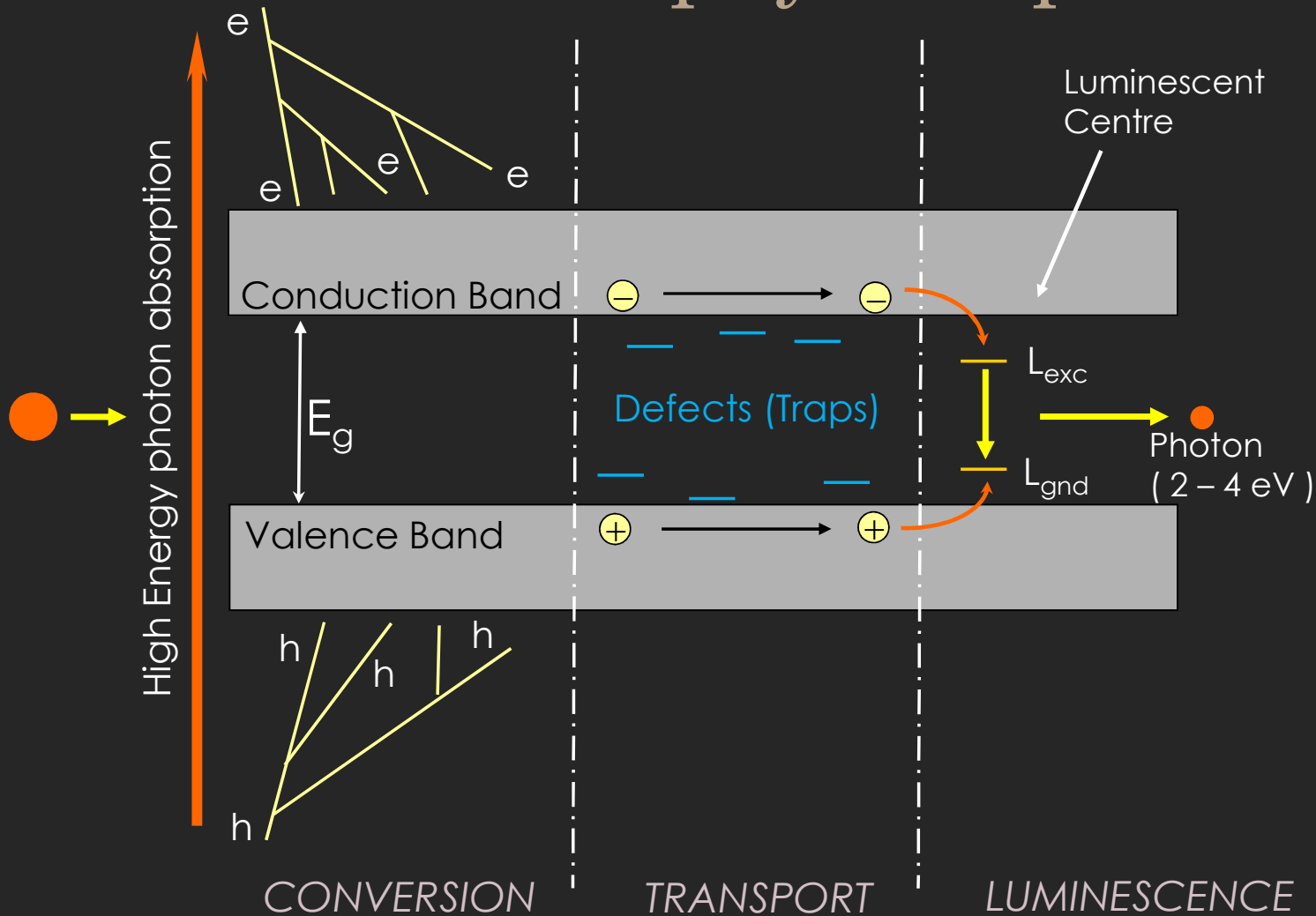
## Lasers

The lasering process does not involve the delocalized bands.

### Critical defects:

- colour centres
- non radiative recombination paths
- scattering centres

# Scintillators: physical process



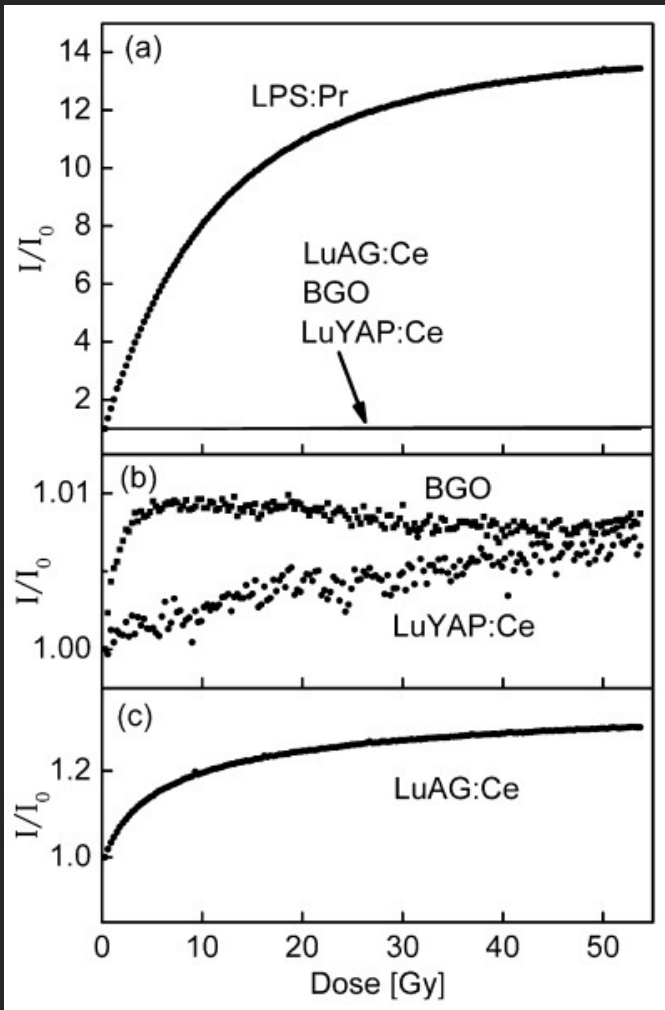
## Scintillators

Defects can **also** act as charge traps during the transport stage

### Critical defects:

- colour centres
- non radiative recombination paths
- scattering centres
- **traps**

# Deep traps in scintillators

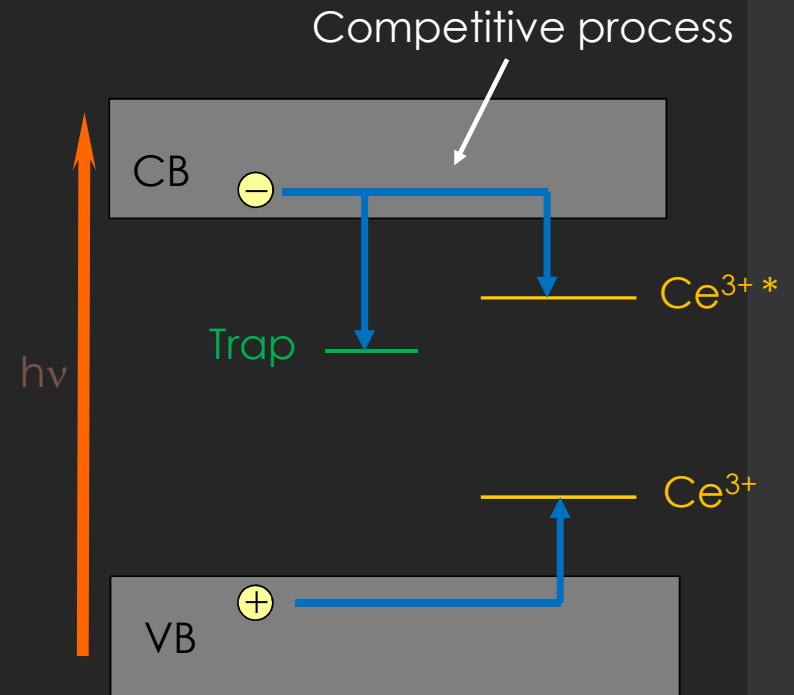


Effects on luminescence properties:

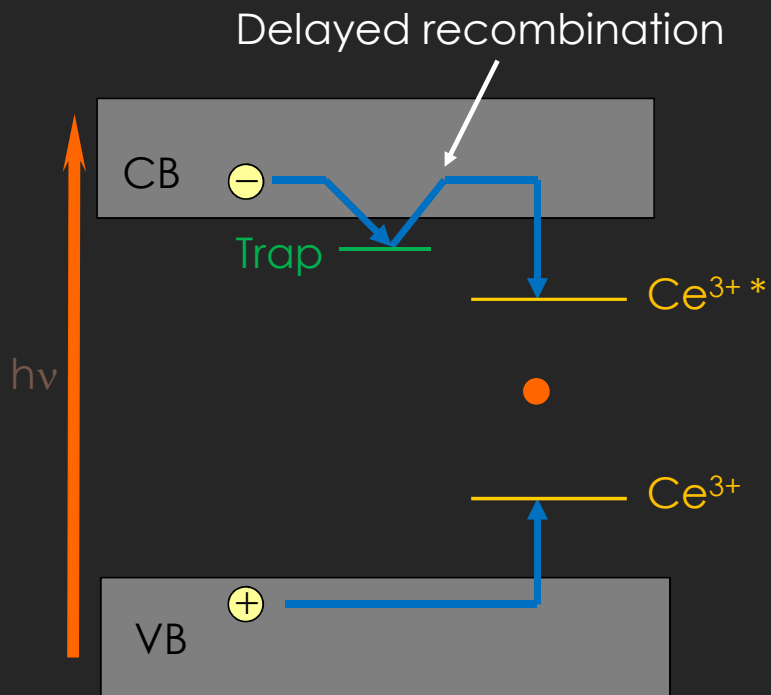
- Reduced light yield
- Bright burn

Room temperature RL efficiency of several crystals versus irradiation dose. Data are normalized to the respective initial value.

*E. Dell'Orto et. al., J. Phys. Chem. C (2013), 117, 20201*

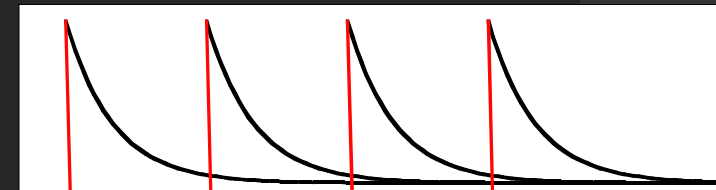
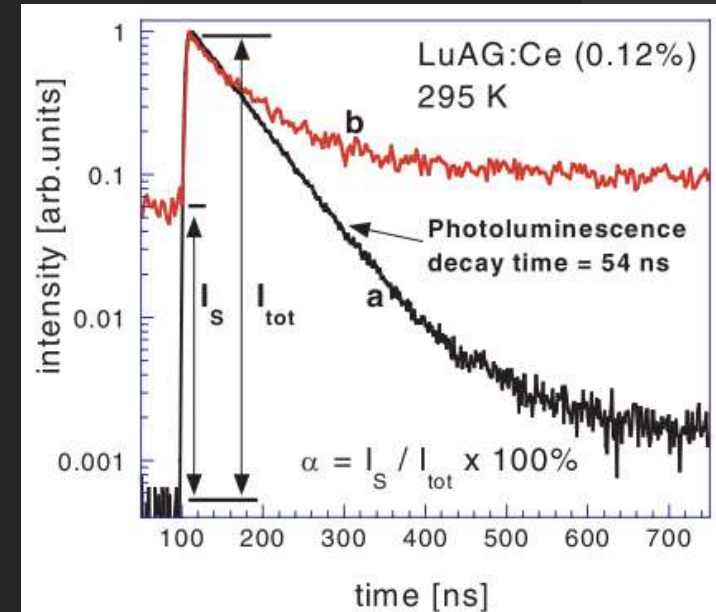


# Shallow traps in scintillators



Effects on luminescence properties:

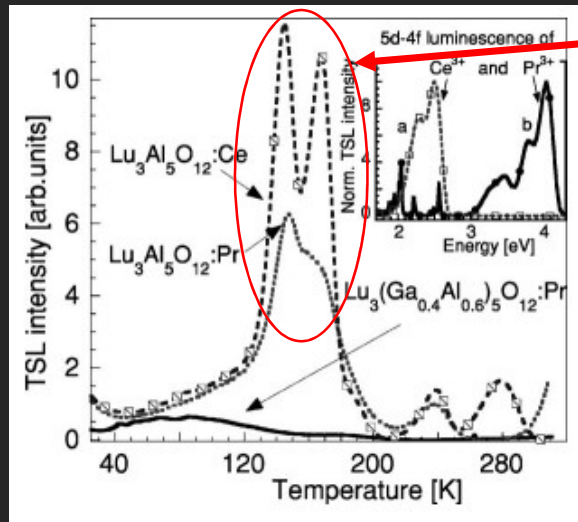
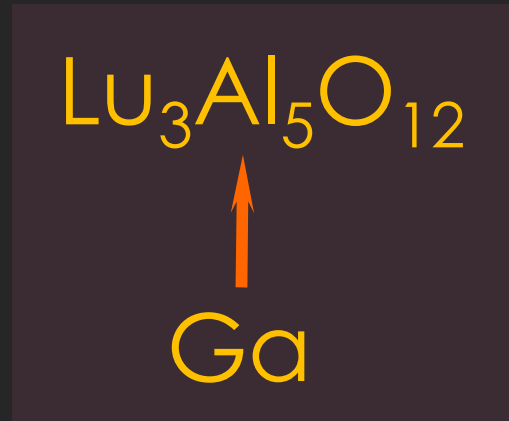
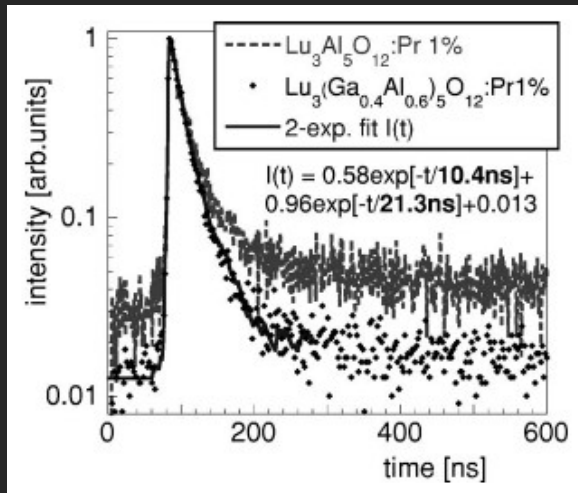
- Slow decay component
- Afterglow



phys. stat. sol. (b) **242**, No. 14, R119–R121 (2005) / DOI 10.1002/pssb.200541225

phys. stat. sol. (a) **202**, No. 2 (2005) / www.pss-a.com

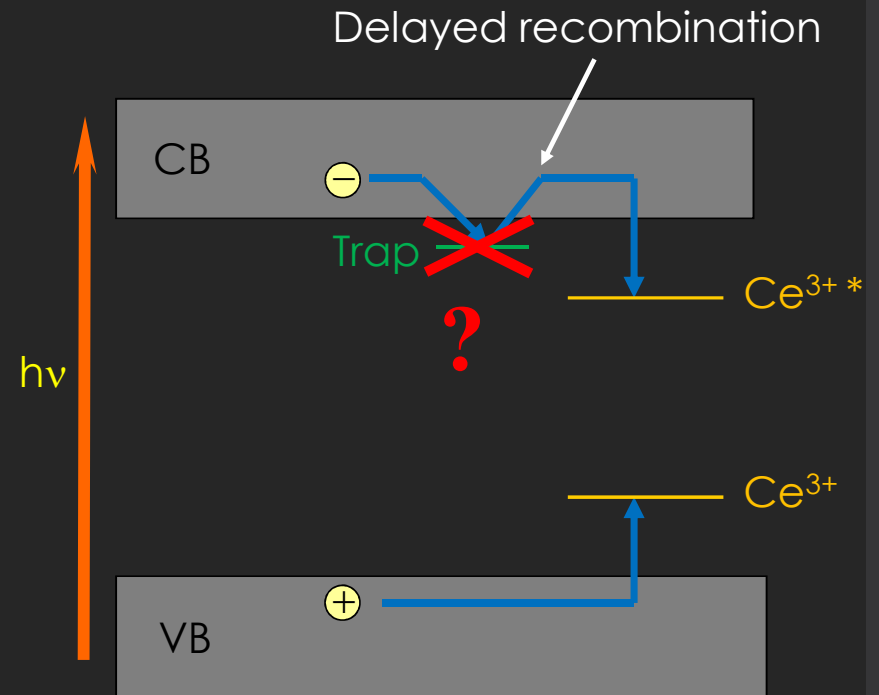
# Shallow traps “removal”



Antisite  
 $E = 0.29 \text{ eV}$

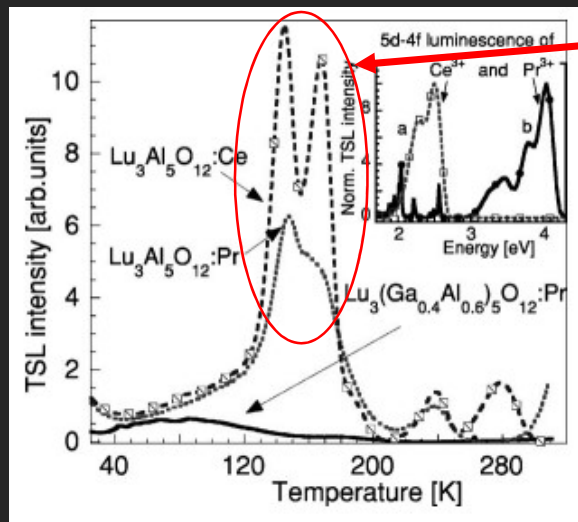
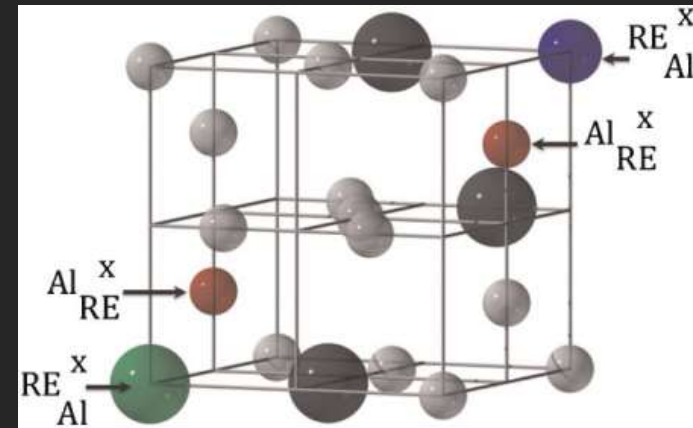
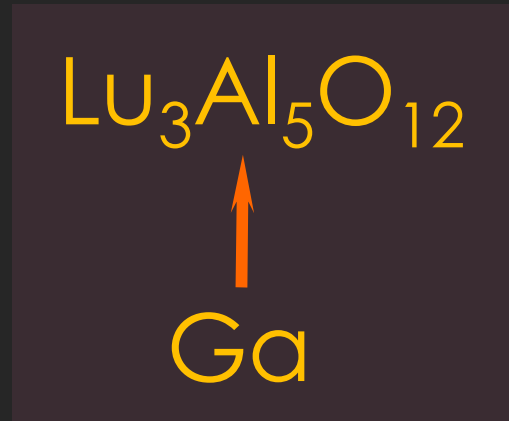
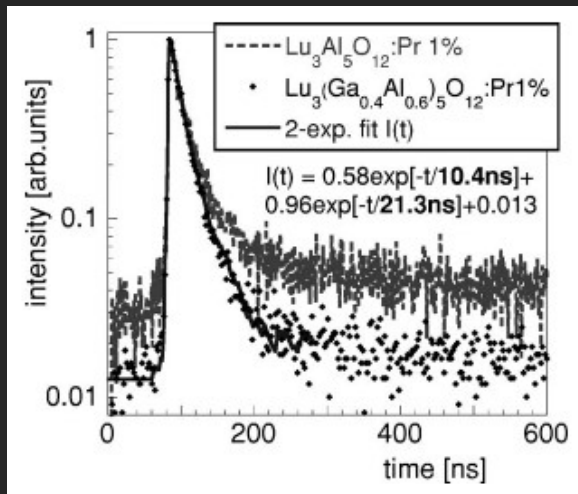
- **Substitution** of **Al** with **Ga** ions (40%) was shown to **remove** both the **slow** scintillation **component** and the **antisite TSL peaks**.

APPLIED PHYSICS LETTERS 88, 141916 (2006)



Why ?

# Shallow traps “removal”

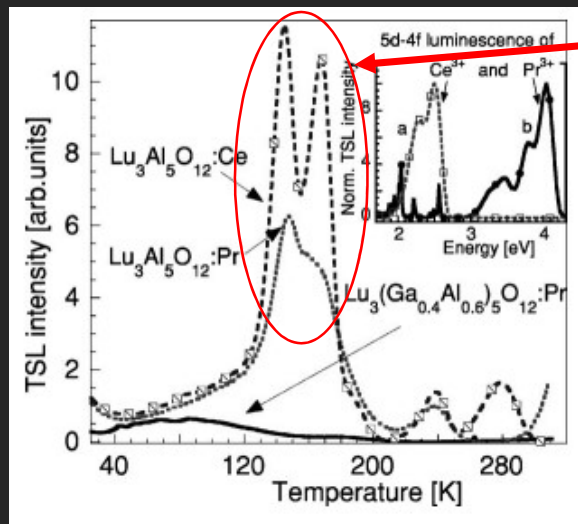
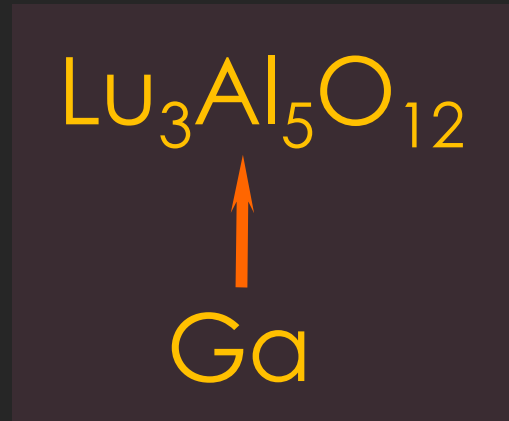
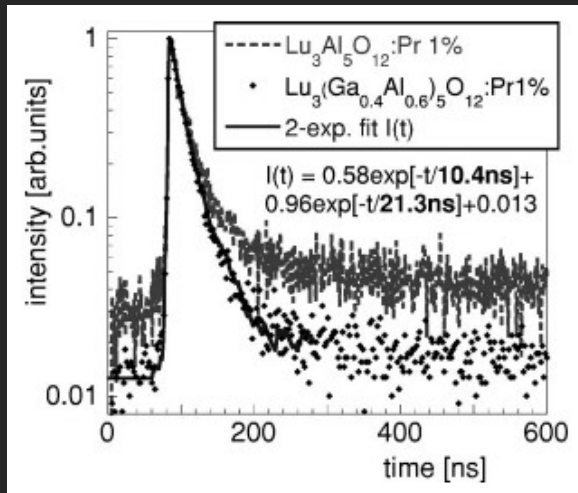


Antisite  
E = 0.29 eV

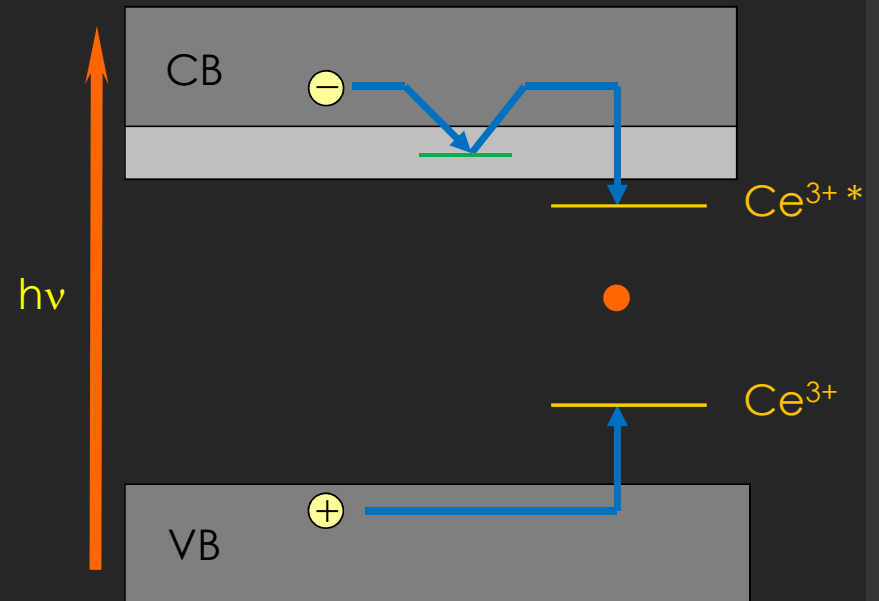
Atomistic simulations showed that the addition of Ga to  $\text{RE}_3\text{Al}_5\text{O}_{12}$  garnets generally lowers the cation antisite defect formation energy, thus suggesting that **Ga additions** should lead to a **higher concentration of antisite defects**

C.R. Stanek et al.  
Phys. Status Solidi B **250**, No. 2, 244–248 (2013)

# Shallow traps “removal”

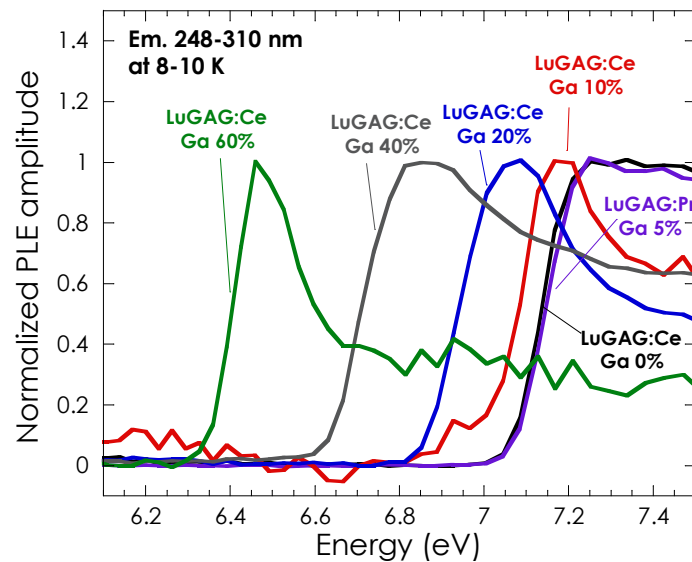
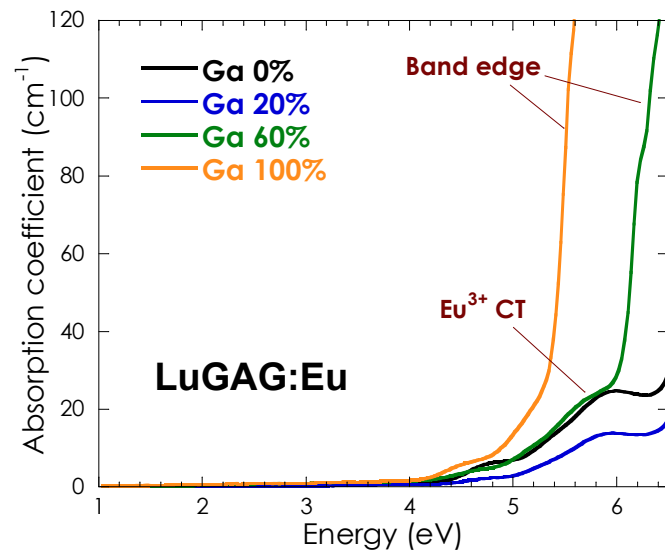


Antisite  
 $E = 0.29 \text{ eV}$



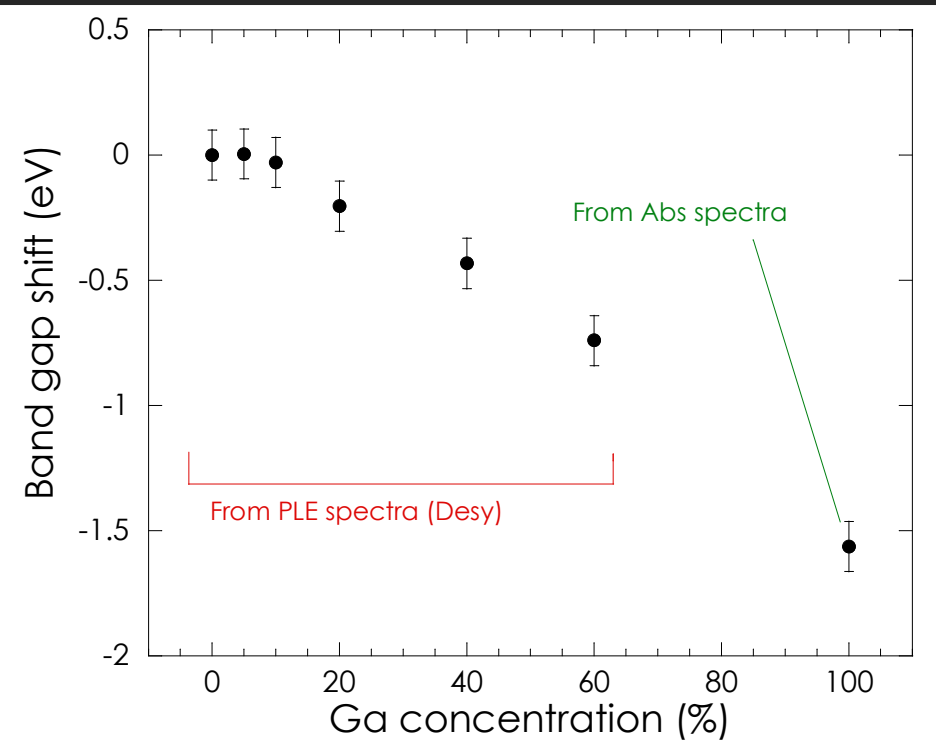
Is the removal of the delayed recombination due to a CB shift ?



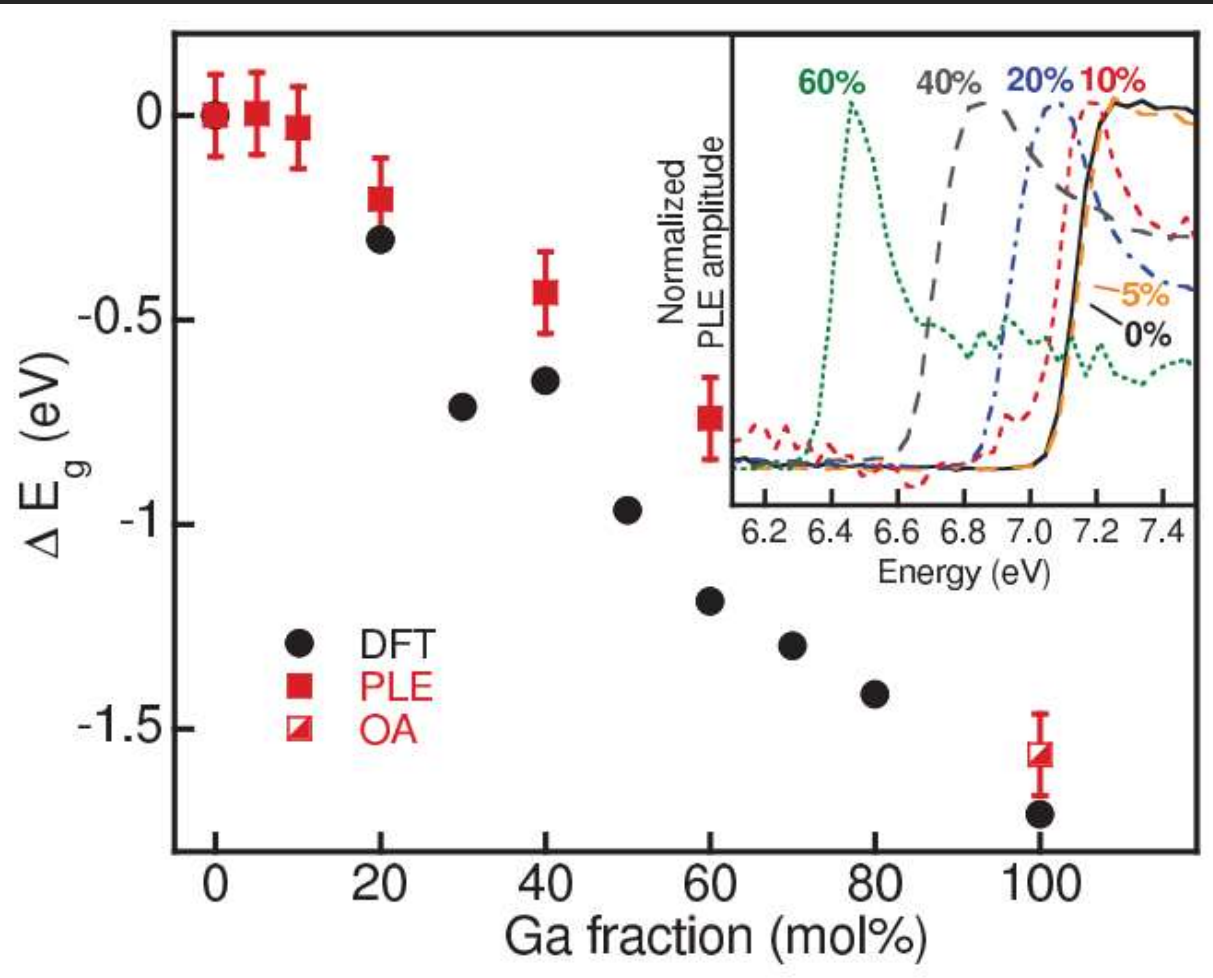


# Band Gap shrinking

- Ga substitution induces a band gap shrinking evidenced by a low energy shift of the absorption edge in UV-VIS OA and in VUV-PLE.



# DFT vs Exper. - Band Gap



## DFT Calculations (C. Stanek - Los Alamos)

- VASP (Vienna Ab Initio Simulation Package). PAW PBE potentials.
- DFT calculations, as expected, underestimate the band gap value (3.85 eV).
- The band gap shrinking is nevertheless reliable and in good agreement with the experimental data obtained from absorption and photoluminescence excitation spectra.

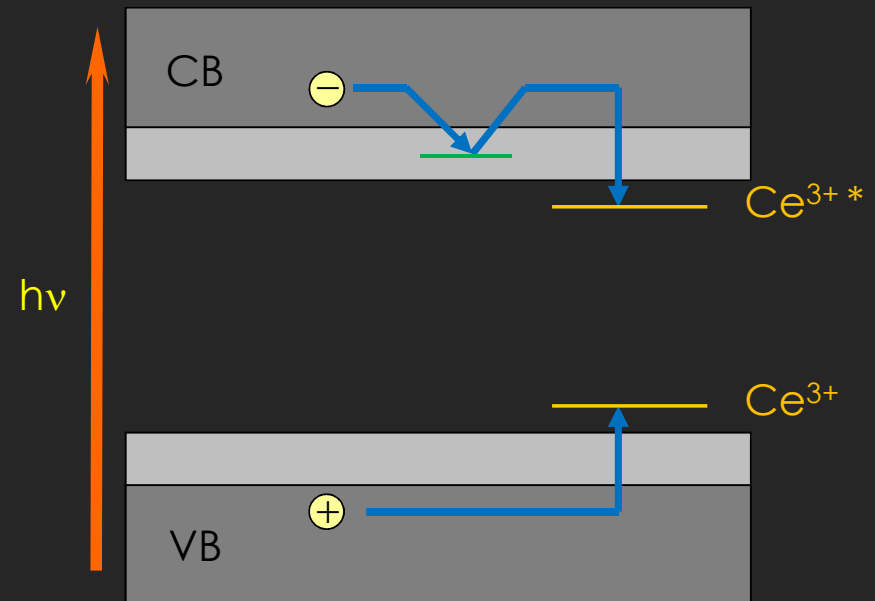
# Band gap shrinking

Is the band gap shrinking evidenced by **OA** due to:

- Shift of the CB?
- Shift of the VB?
- Both?



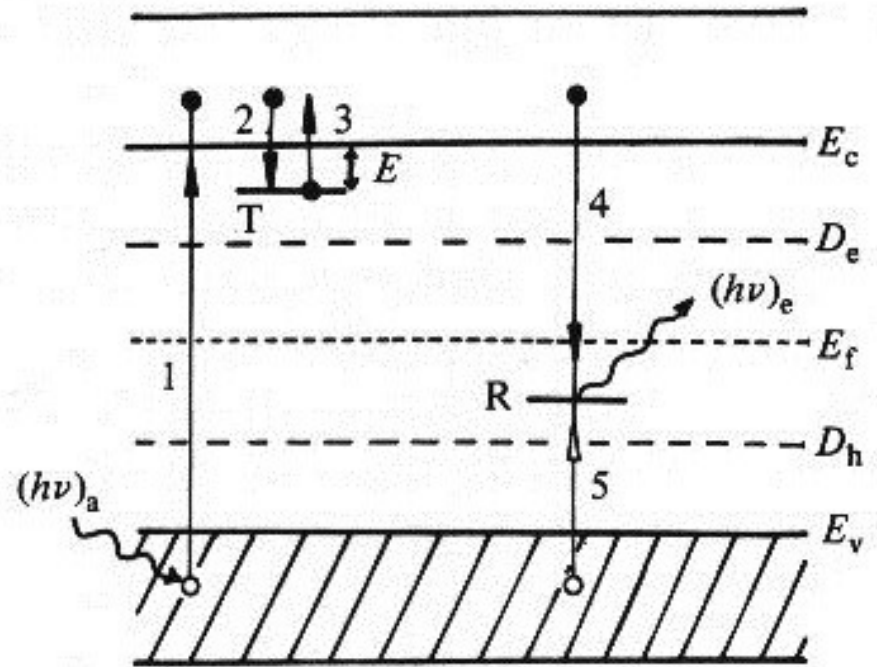
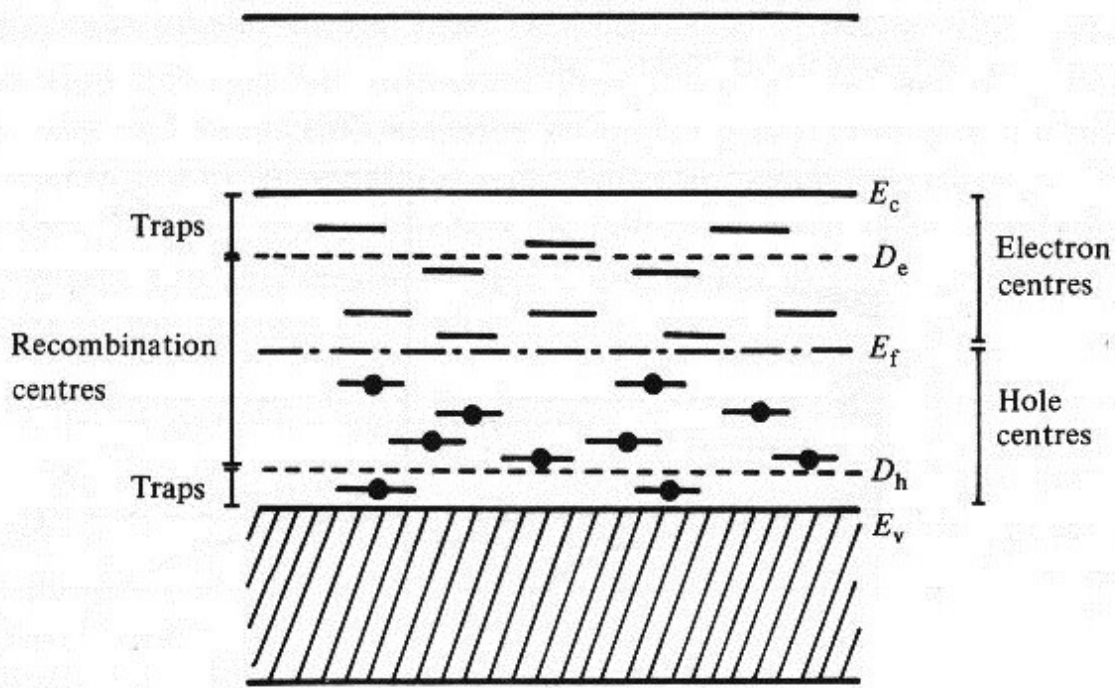
We need a different technique



# Outline

- Thermoluminescence mechanism
- Delocalized bands shift
- Localization of the excited levels of a luminescence centre

# Traps and recombination centres

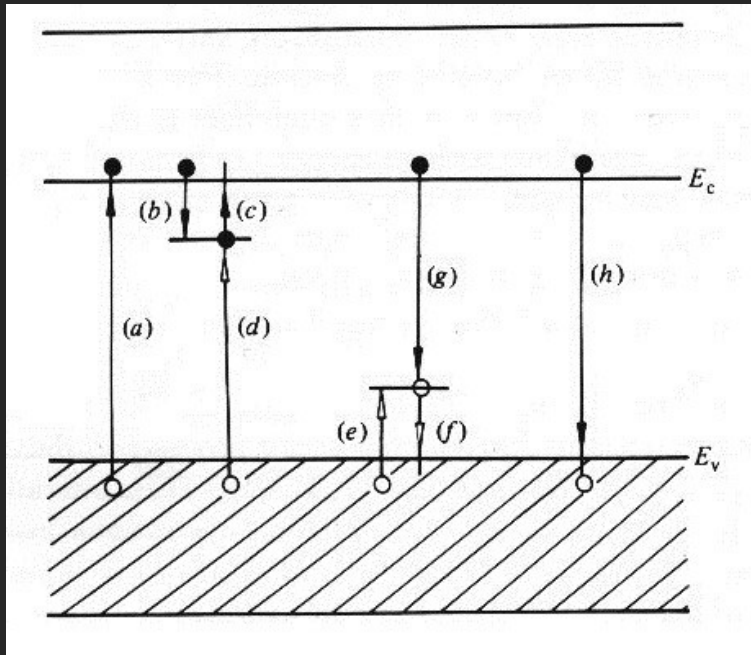


## Detrapping probability

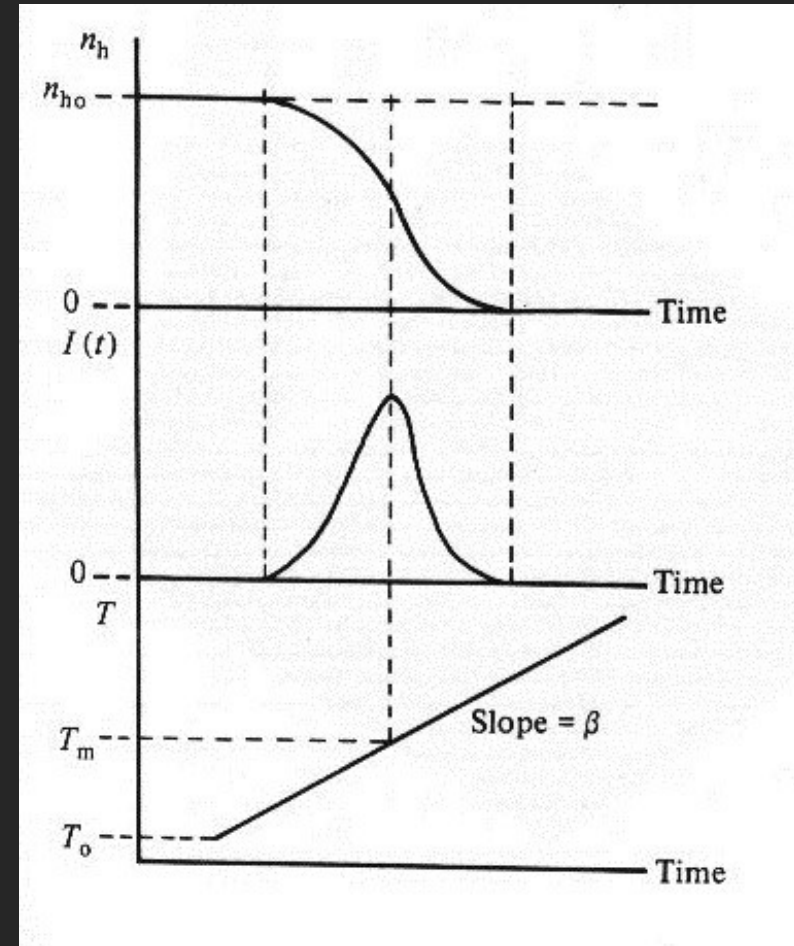
$$p = \tau^{-1} = s \exp(-E/kT).$$

McKeever S.

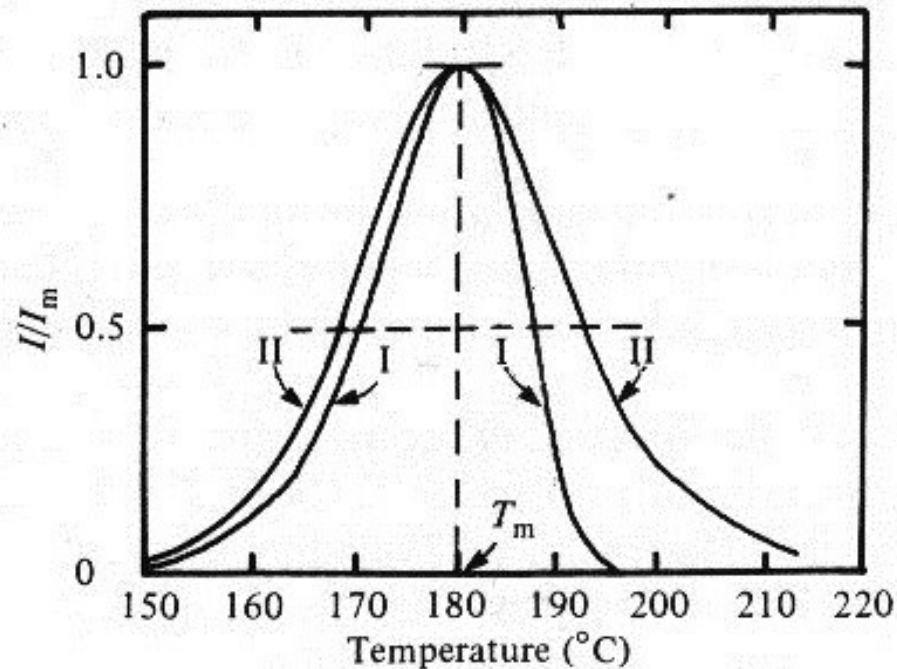
# Thermally Stimulated Luminescence



- Irradiation
- Heating at a constant rate
- Light detection vs. temperature (glow curve)



# TSL Kinetics Orders



I Order kinetics

$$I(T) = n_0 s \exp(-E/kT) \exp \left[ - (s/\beta) \int_{T_0}^T \exp(-E/kT) dT \right],$$

II Order kinetics

$$I(T) = n_0^2 s' \exp(-E/kT) / \left[ 1 + (n_0 s' / \beta) \int_{T_0}^T \exp(-E/kT) dT \right]^2$$



# Initial rise technique

I Order kinetics

$$I(T) = n_0 s \exp(-E/kT) \exp\left[-(s/\beta) \int_{T_0}^T \exp(-E/kT) dT\right],$$

II Order kinetics

$$I(T) = n_0^2 s' \exp(-E/kT) \left[ 1 + (n_0 s' / \beta) \int_{T_0}^T \exp(-E/kT) dT \right]^2$$

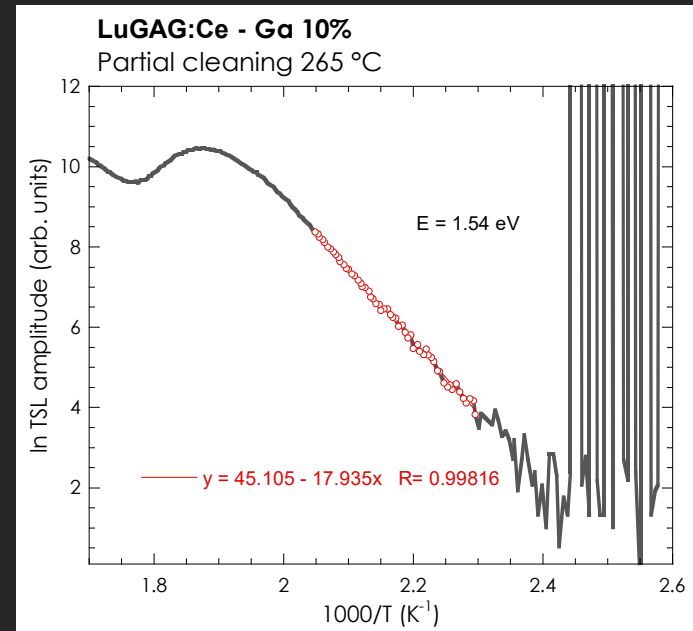
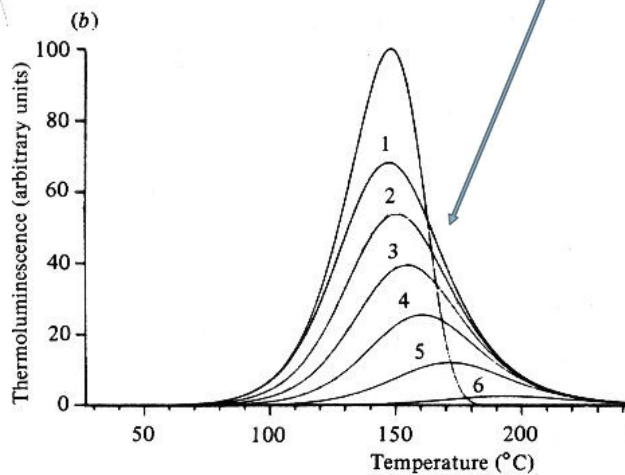
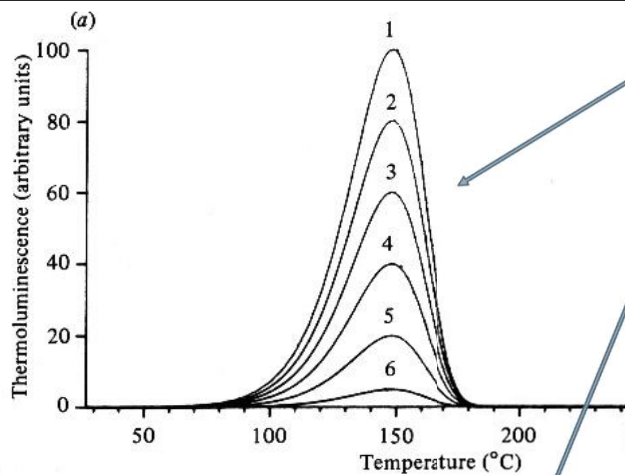
Allows the evaluation of the trap thermal depth regardless of the kinetics order

C.B.

e trap  $\Delta E$

h trap  $\Delta E$

V.B.





# Outline

- Thermoluminescence mechanism
- Delocalized bands shift
- Localization of the excited levels of a luminescence centre

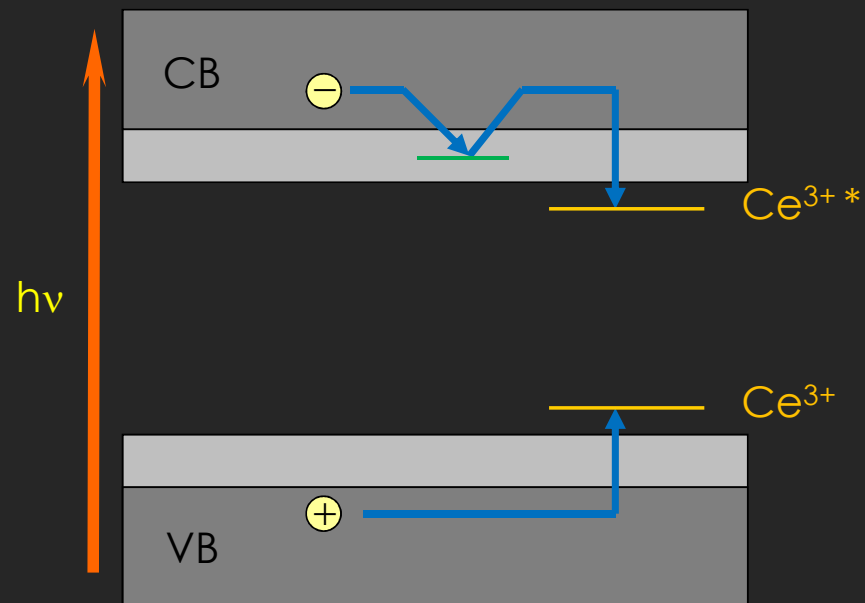
# Band gap shrinking

Is the band gap shrinking evidenced by **OA** due to:

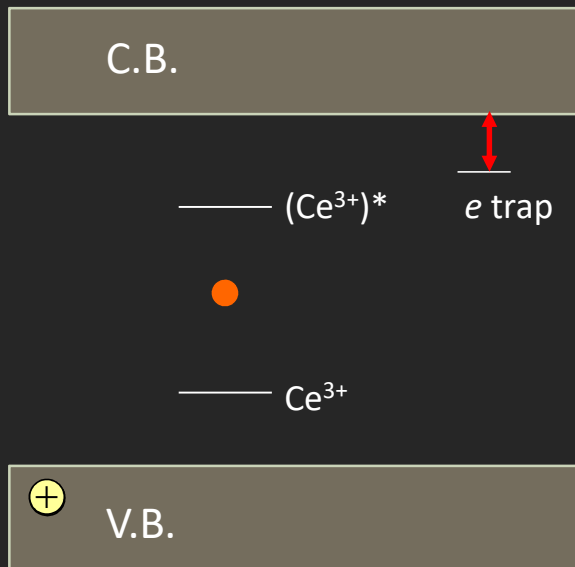
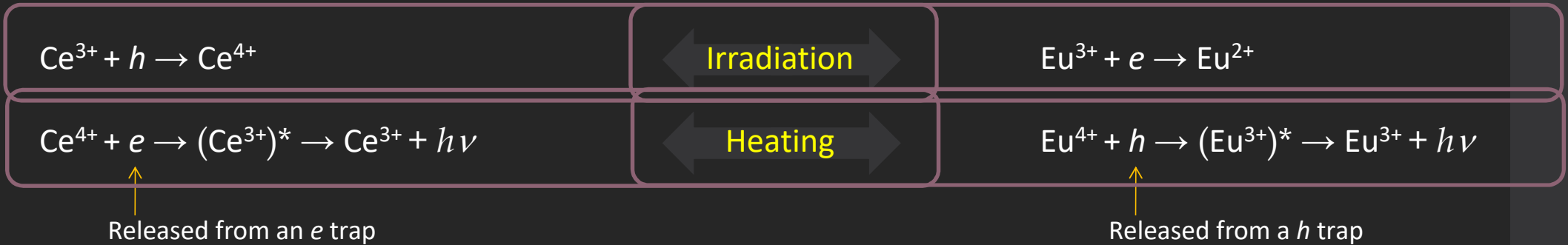
- Shift of the CB?
- Shift of the VB?
- Both?



We need a different technique

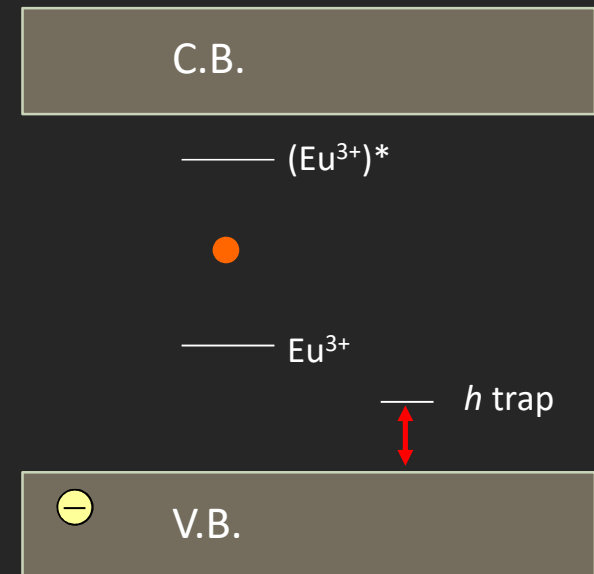


# Thermoluminescence mechanism (Ce, Eu)



## TSL and traps type

- $Ce^{3+}$  emission is observed whenever an **electron** is released from a trap.
- $Eu^{3+}$  emission is observed whenever a **hole** is released from a trap.



# $\text{Lu}_3\text{Ga}_x\text{Al}_{5-x}\text{O}_{12}$ Samples

- $\text{Lu}_3\text{Ga}_x\text{Al}_{5-x}\text{O}_{12}$  (LuGAG) single crystals grown by micro pulling down (m-PD) technique at the University of Tokyo (Japan)
- Crystals size: 6 x 4 x 1 mm<sup>3</sup> approximately

## LuGAG:Ce

Ce: 0.7 mol% (in the melt)

Ga: 0%, 10%, 20% and 40%

## LuGAG:Eu

Ce: 0.1 mol% (in the melt)

Ga: 0%, 20%, 60% and 100%

# Working assumption

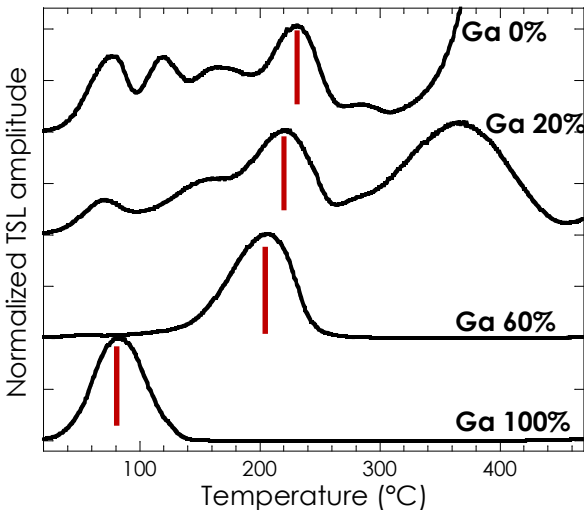
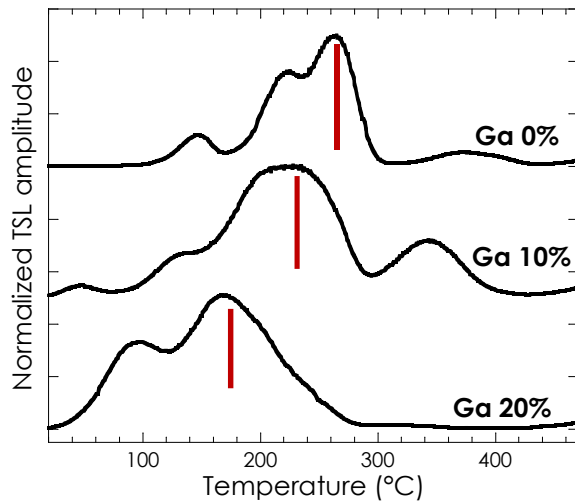
- We assume the e and h traps energy levels as fixed.
- A change in the TSL thermal activation energy of an e trap (h trap) can thus be an approximate evaluation of the C.B. (V.B.) shift.



But let's not forget that:

- The C.B. and V.B. are not flat.
- The thermal activation energy is not directly comparable with the optical transition energy.
- The traps themselves could be affected by Ga substitution.

# TSL glow curves



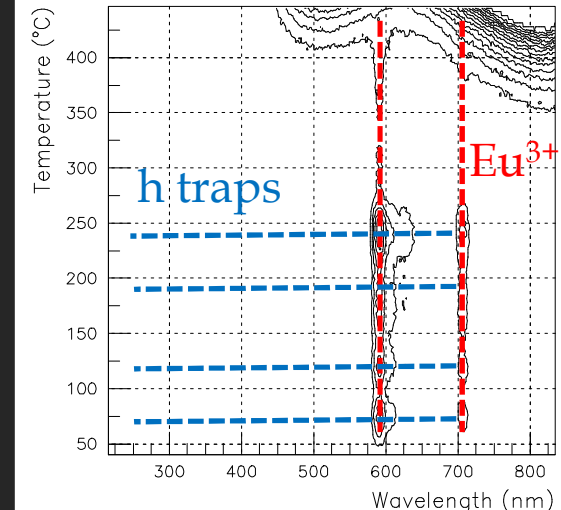
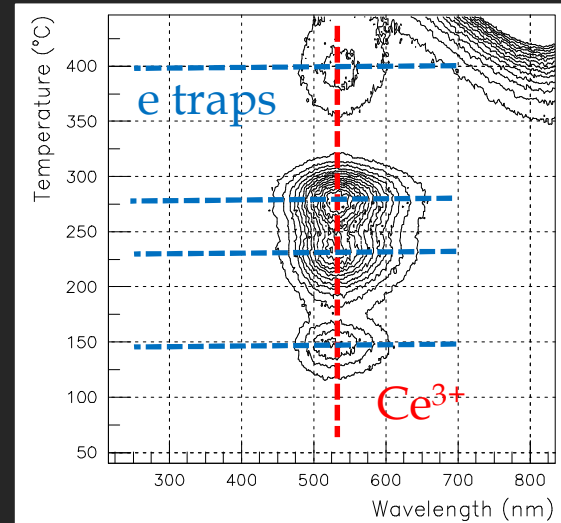
LuGAG:Ce

(CB shift)

As expected, Ga substitution induces a low temperature shift of the TSL peaks in both Ce- and Eu-doped LuGAG samples.

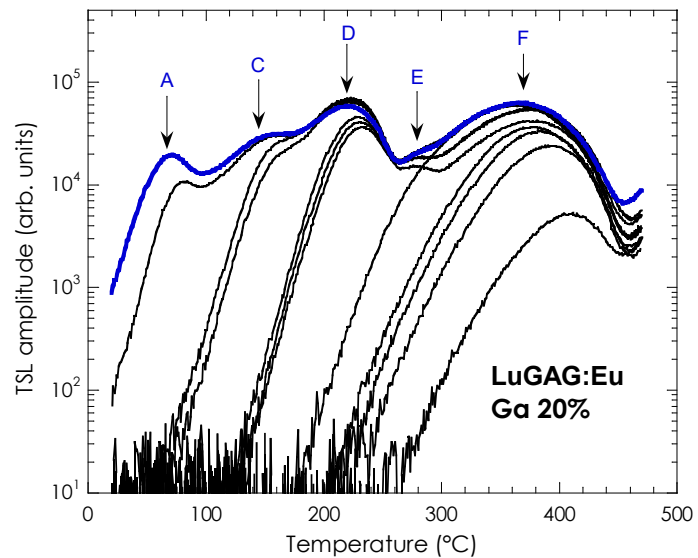
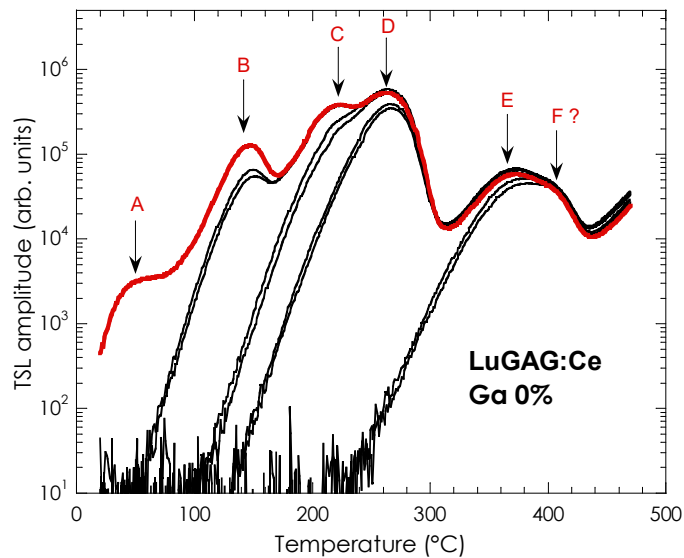
LuGAG:Eu

(VB shift)

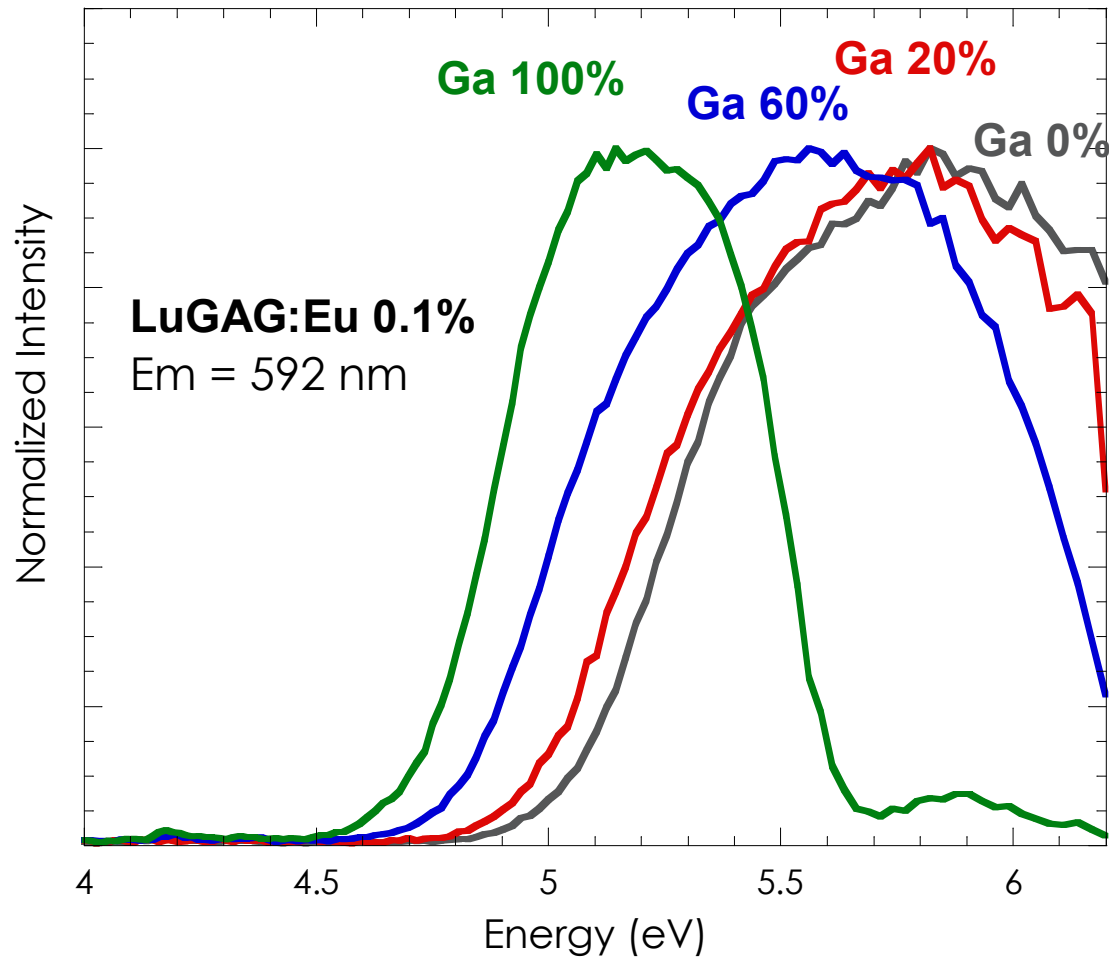


# Initial rise technique

- Several TSL peaks can be identified in the glow curves.
- The thermal activation energies of the TSL peaks were evaluated by means of the initial rise technique

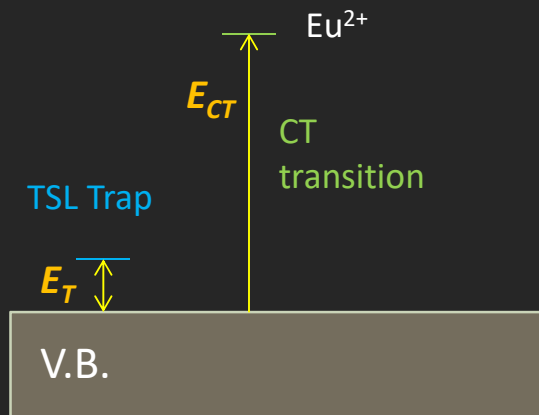


# Charge transfer band (CT)



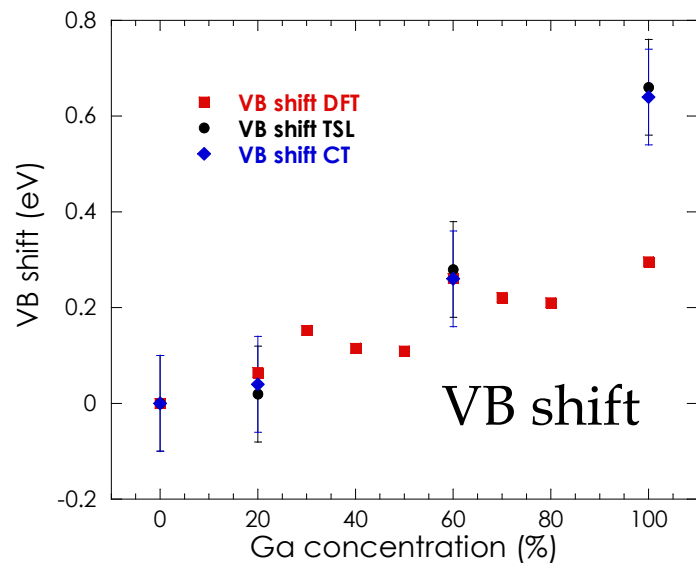
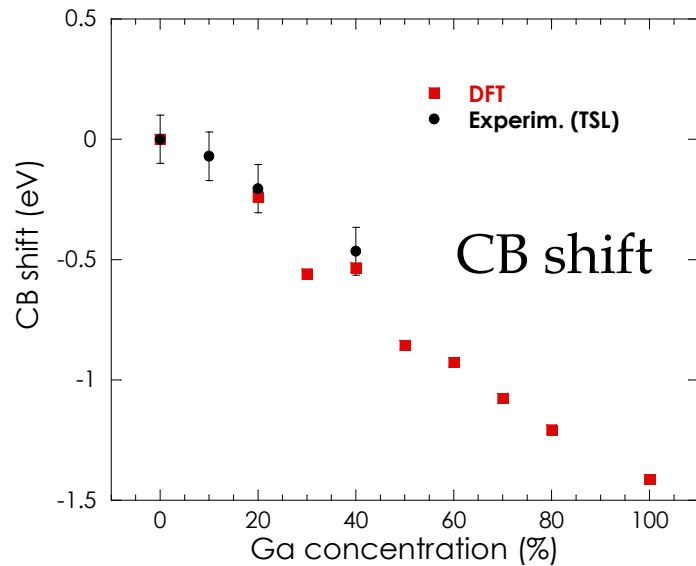
- The CT band allows the monitoring of the V.B. shift independently from TSL data.

C.B.





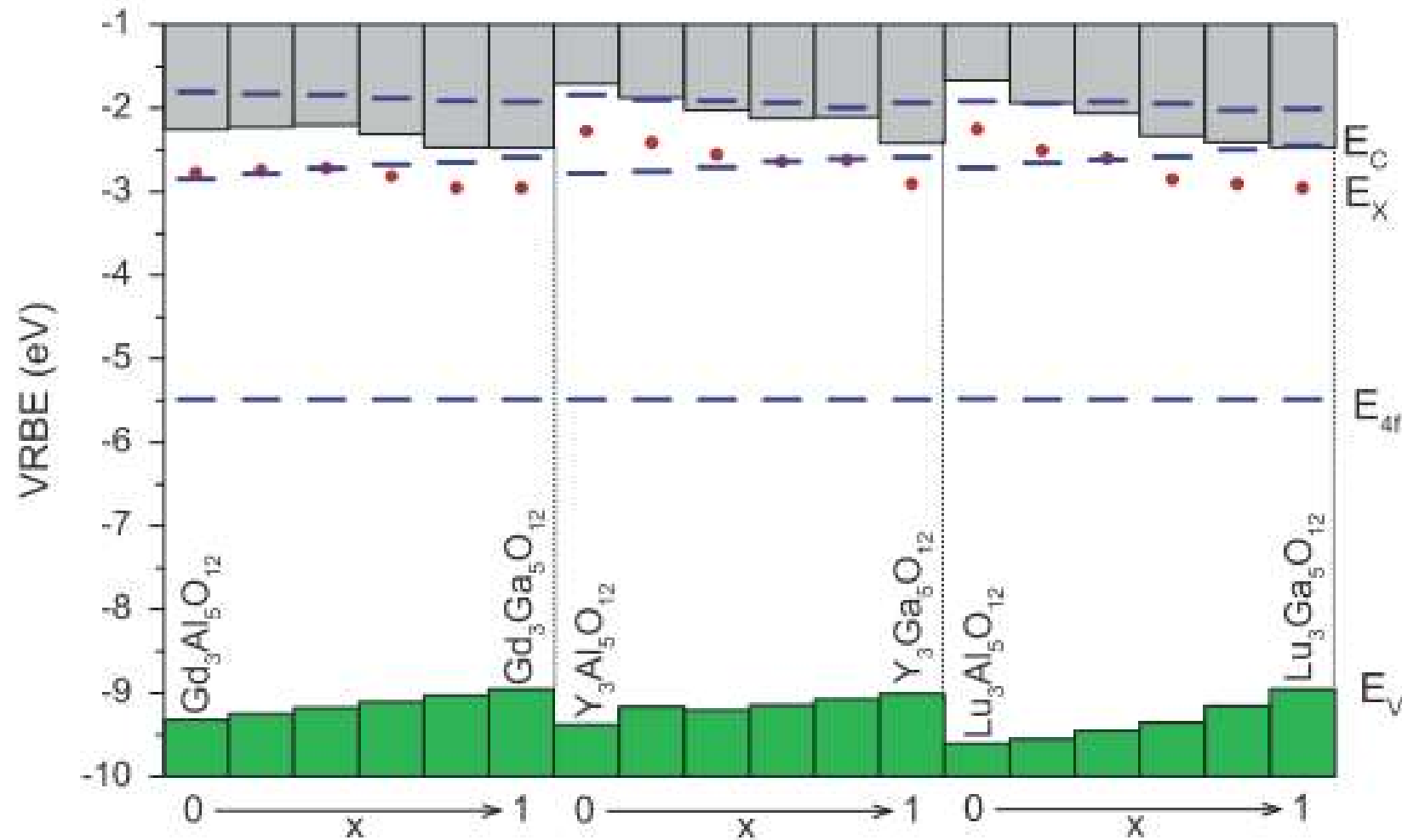
# DFT vs Experiment



- DFT calculations and TSL data are in good agreement on both the C.B. and V.B. shift.
- A significant discrepancy is observed for the V.B. shift of the 100% Ga sample
- Ce doped LuGAG with a higher Ga content would be useful in order to extend the available experimental data.

*Fasoli et al. Phys. Rev. B, **84**, 081102(R) (2011)*

# Cerium energy levels in garnets

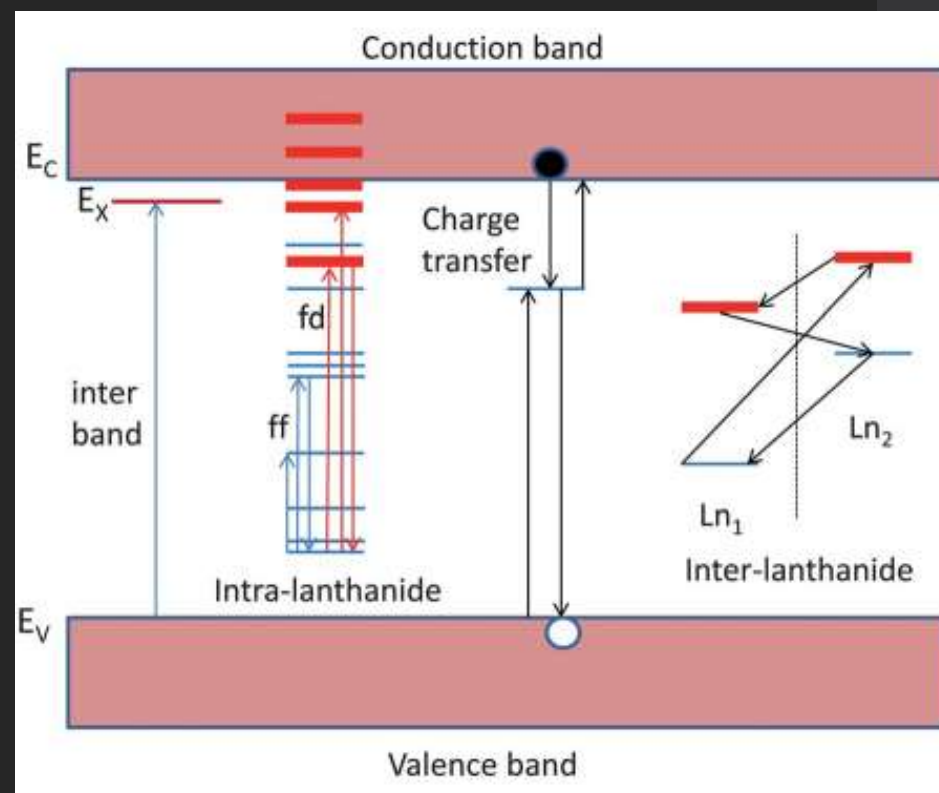
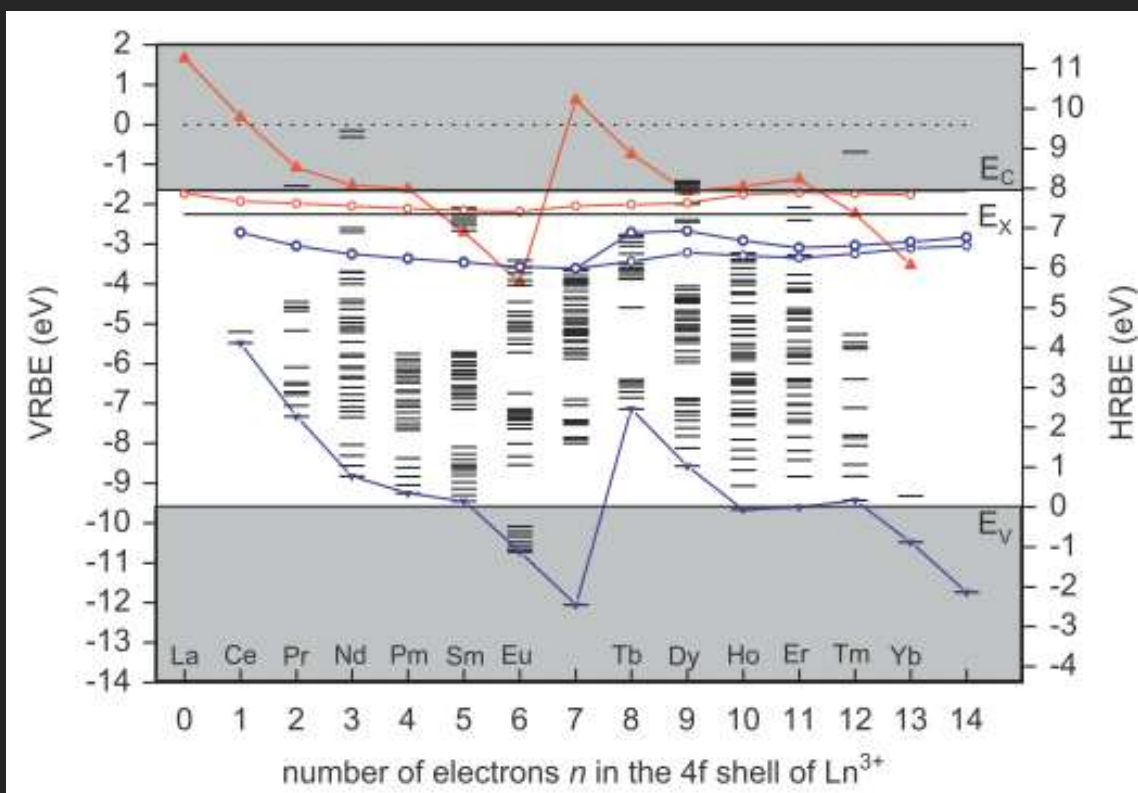


P. Dorenbos,  
J. Lumin.  
**134** (2012) 310

# Outline

- Thermoluminescence mechanism
- Delocalized bands shift
- Localization of the excited levels of a luminescence centre

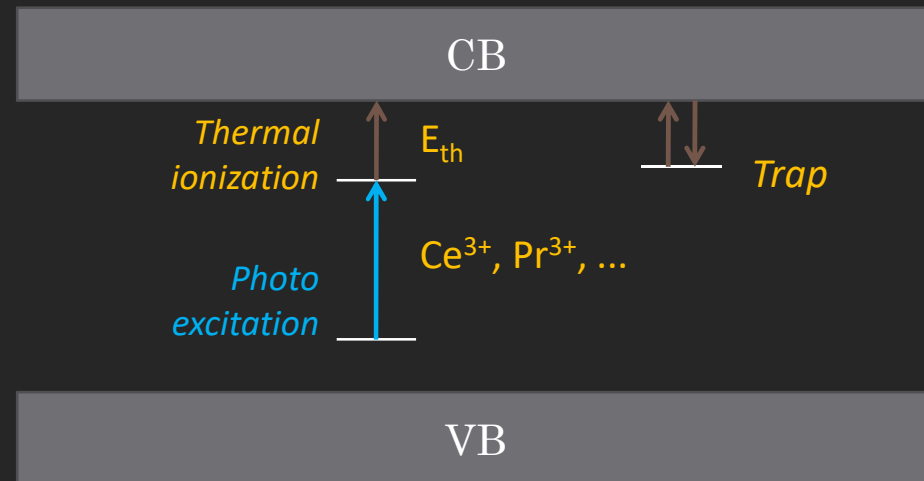
# Rare earths energy levels



P. Dorenbos, J. Mater. Chem. **22**, 42 (2012) 22344

# Thermal ionization of the luminescent center

- When the excited level of the luminescence center is close enough to the conduction band, **thermal ionization** can occur.
- Under photo excitation of the luminescence center the electron can escape from the excited level to the conduction band and, possibly, get **trapped** in localized defects.
- In **bulk** materials the thermal ionization energy barrier  $E_{th}$  can be evaluated by means of **photoconductivity** measurements.
- A different method is required for **powder** samples and **thin films**.



Thermally  
Stimulated  
Luminescence

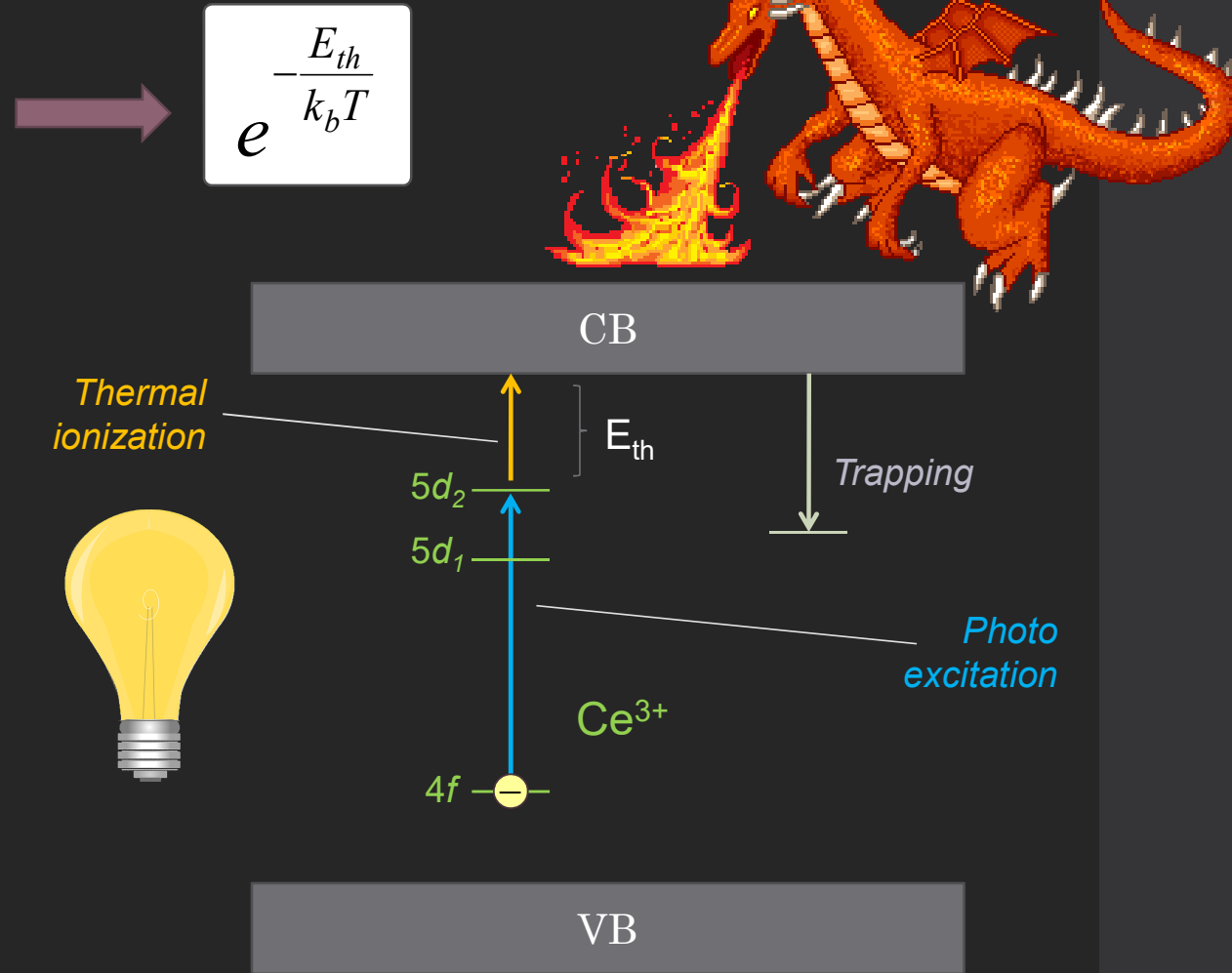
**TSL**

# Ionization energy evaluation

- If we excite, at a given temperature,  $\text{Ce}^{3+}$  in a 4f-5d absorption band, the fraction of electrons thermally promoted to the CB is:
- The fraction of ionized electrons trapped in a stable defect can be evaluated from the TSL glow curve.

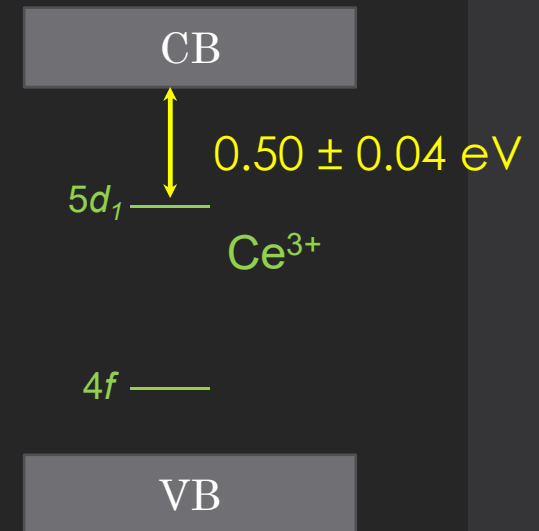
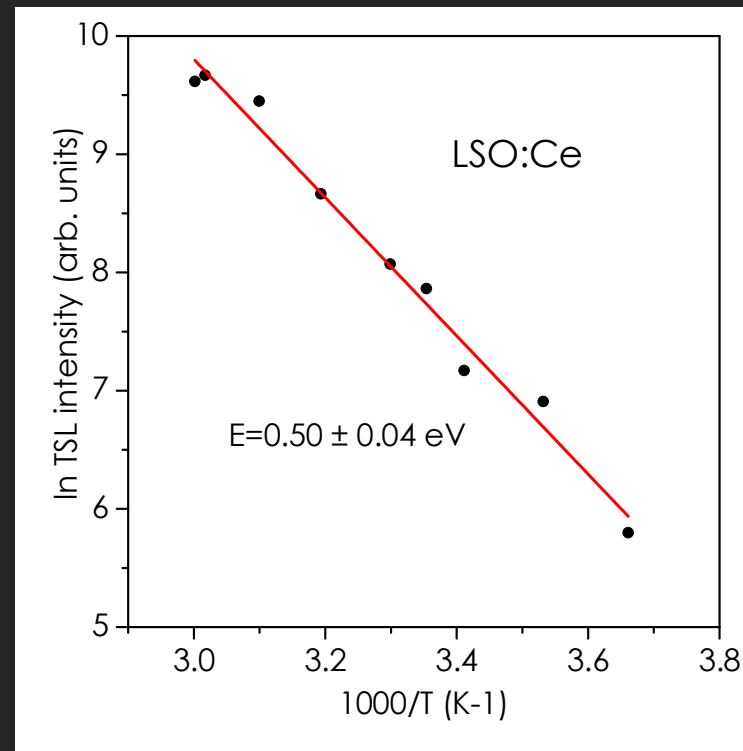
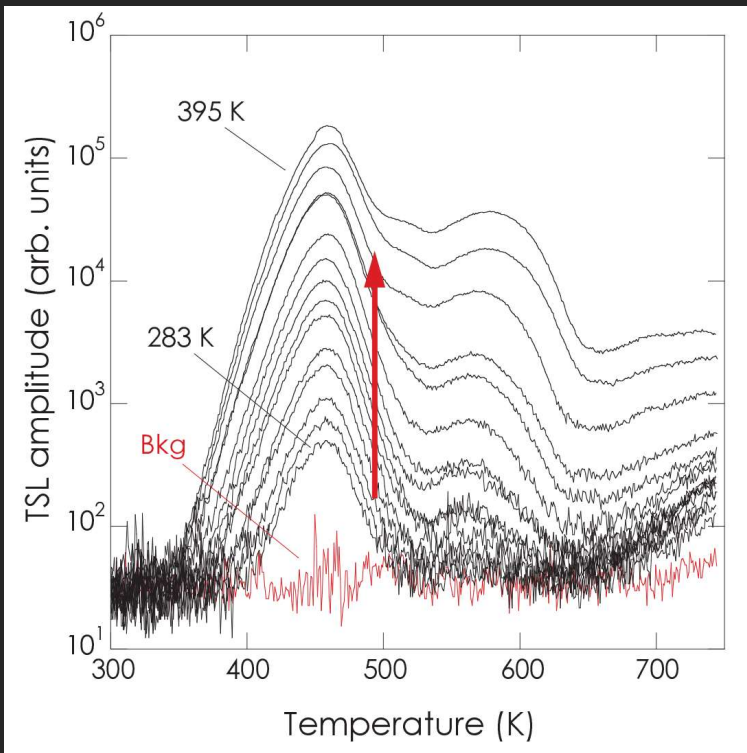
Plotting the **TSL peak intensity** as a function of the **illumination temperature** in an Arrhenius plot the value of the thermal ionization barrier  $E_{\text{th}}$  can be evaluated.

Fasoli et al. Phys. Rev. B, **85**, 085127 (2012)



# Ionization energy evaluation: Example

The energy separation between the CB and the  $5d_1$  level was found to be  $0.50 \pm 0.04$  eV, consistent with the value  $0.45 \pm 0.02$  eV obtained by *van der Kolk et al., APL 83, 9, 1740 (2003)* from photoconductivity data.



# Samples

- $\text{Lu}_3\text{Ga}_x\text{Al}_{5-x}\text{O}_{12}$  (LuGAG) single crystals grown by micro pulling down ( $\mu$ -PD) technique at **Tohoku University(Japan)** by A. Yoshikawa and H. Ogino
- Crystals size: 6 x 4 x 1 mm<sup>3</sup> approximately

## LuGAG:Ce

Ce: 0.7 mol% (in the melt)

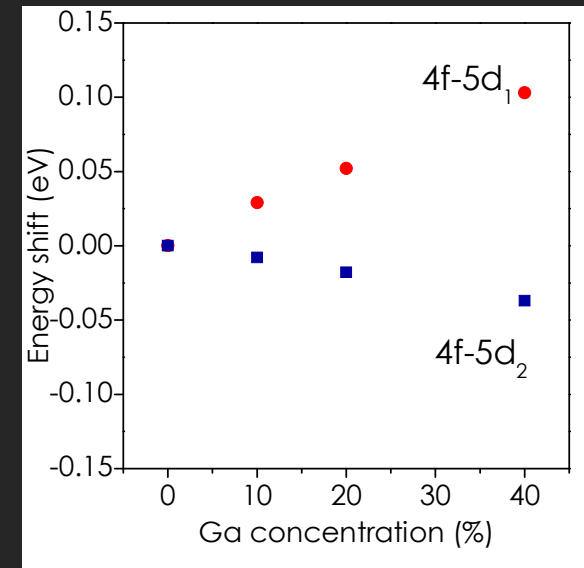
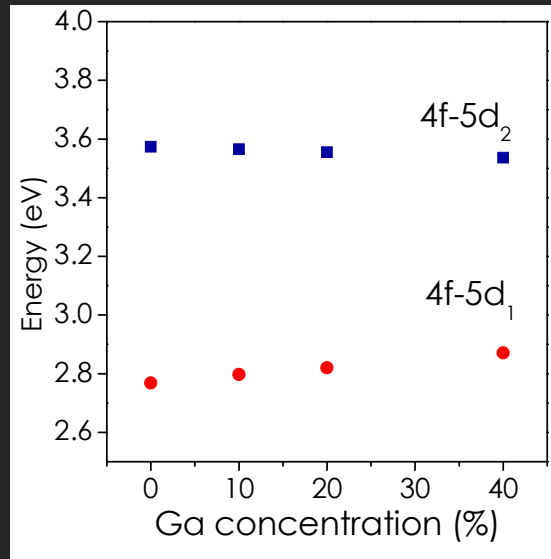
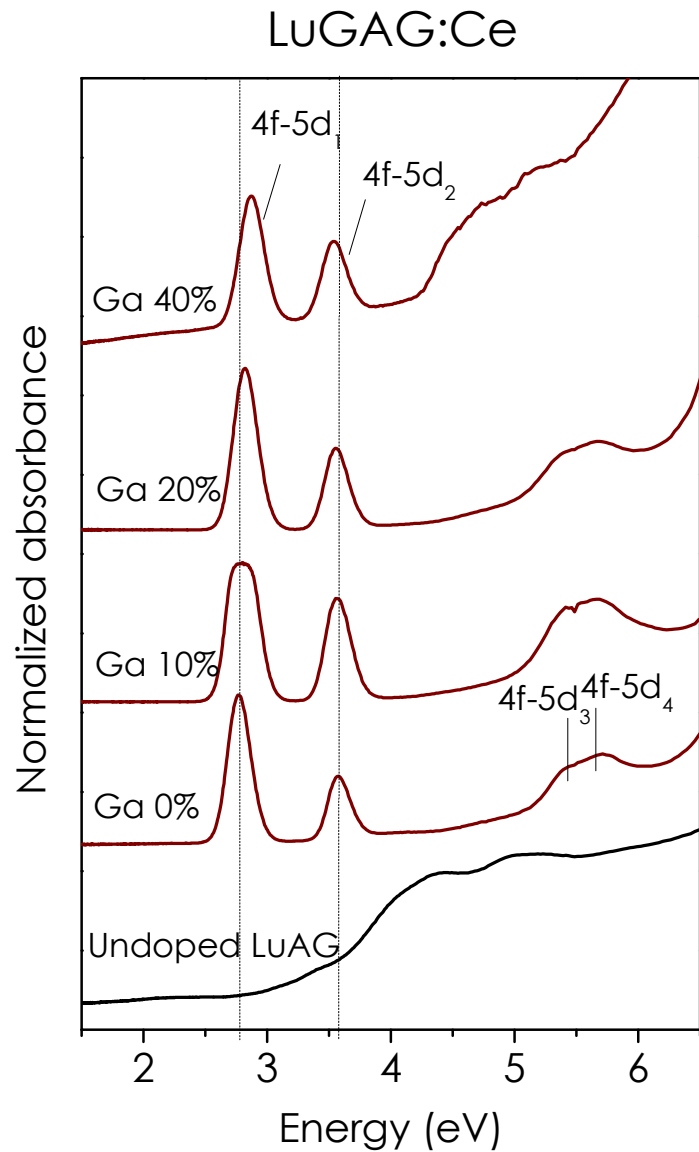
Ga: 0%, 10%, 20% and 40%

# Experimental setup

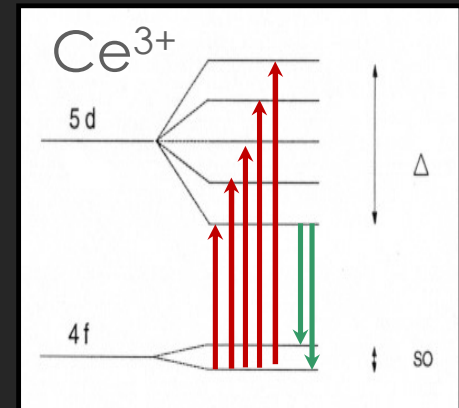
- **Excitation** light was obtained from a Xenon lamp coupled to a double monochromator Gemini, Jobin-Yvon (**FWHM 2 nm**).
- The sample was mounted on a Peltier cell and its temperature was controlled by a **Cooltronic TC2812** Peltier controller.
- TSL glow curves were collected with a 2 °C/s heating rate.



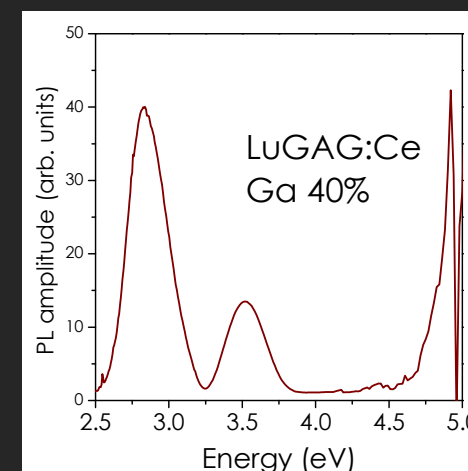
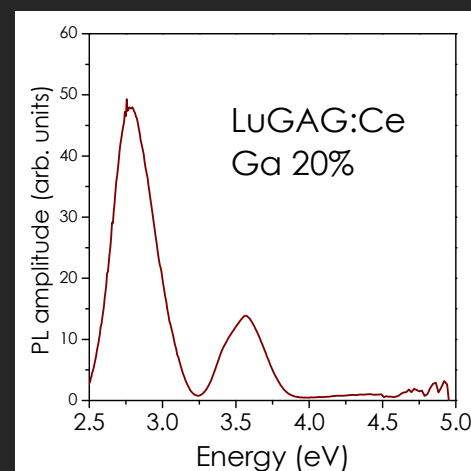
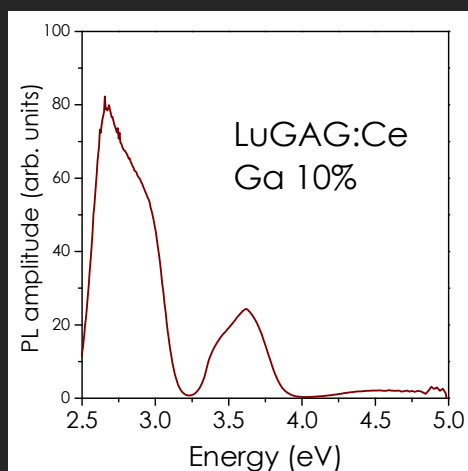
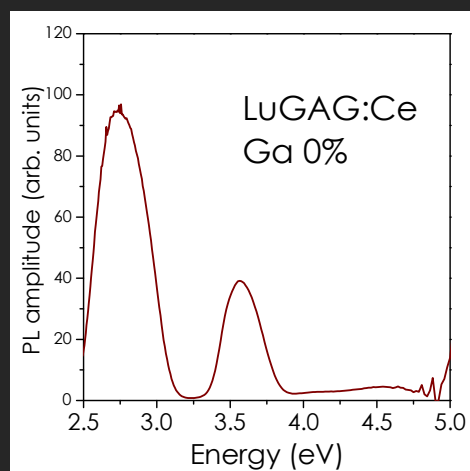
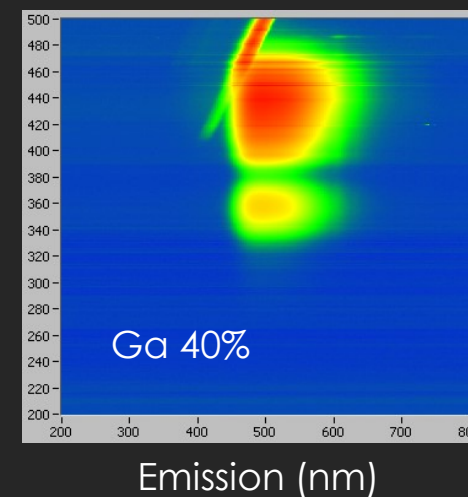
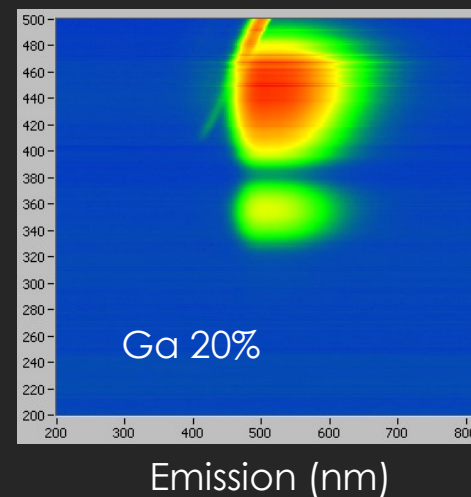
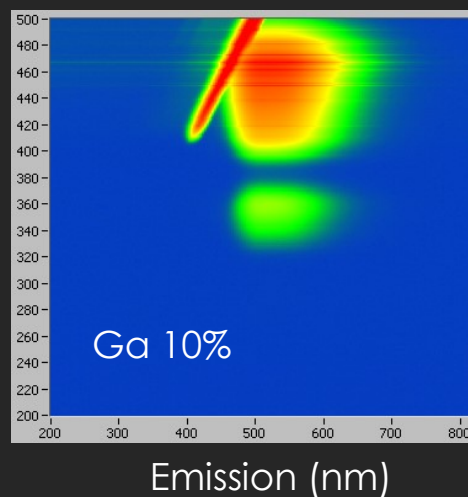
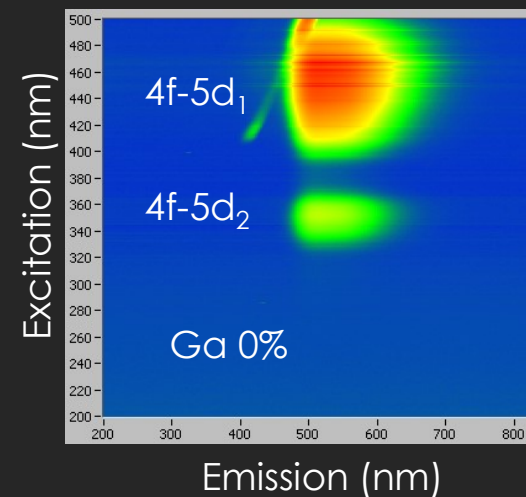
# Optical absorption: energy shift



A progressive shift of 4f-5d Ce transitions was evidenced by optical absorption measurements.



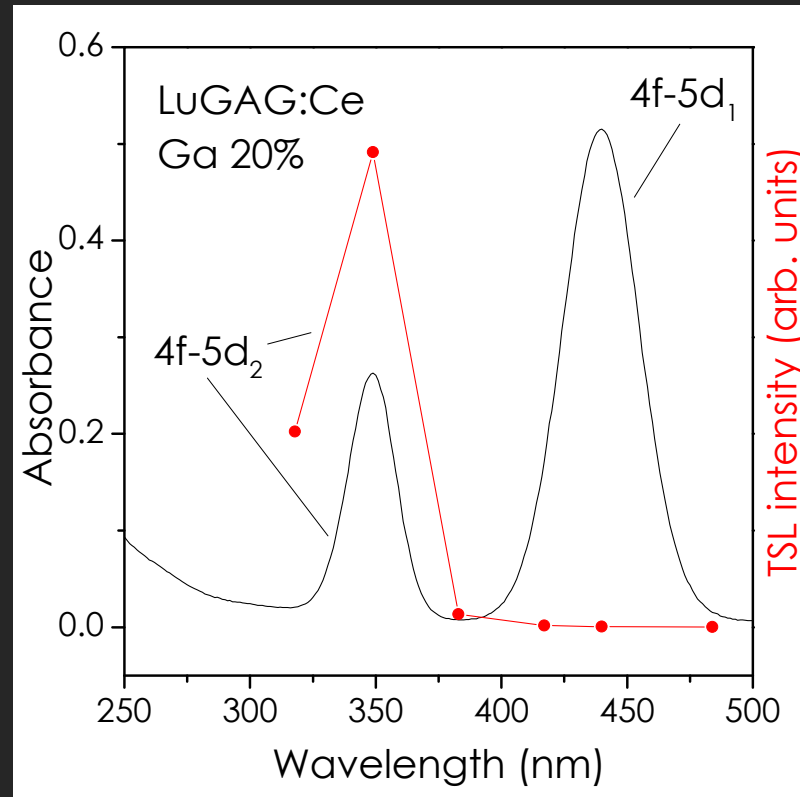
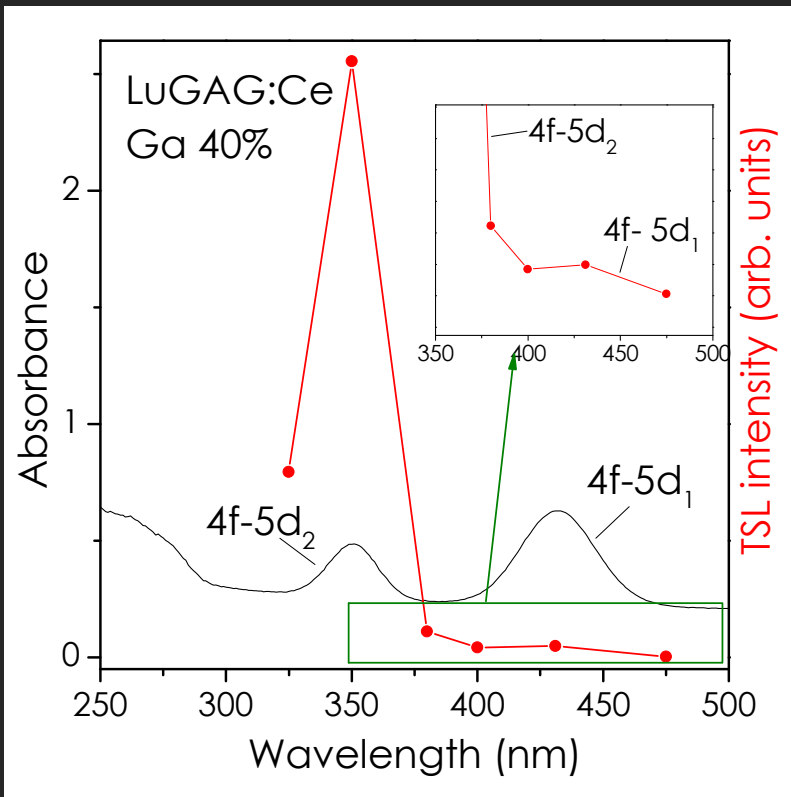
# Photo-luminescence: LuGAG:Ce



PL/PLE

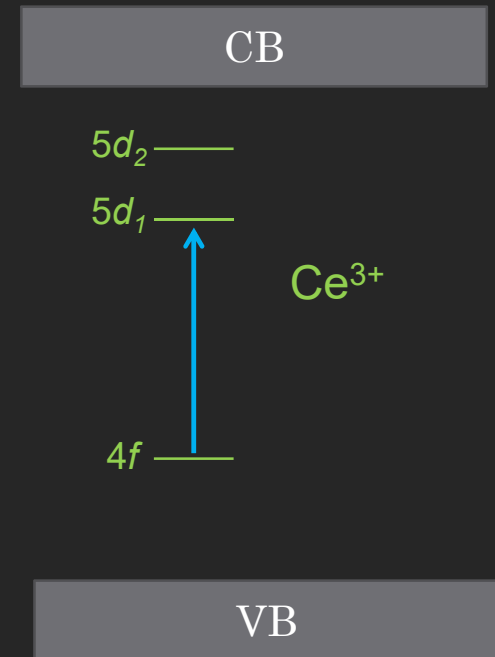
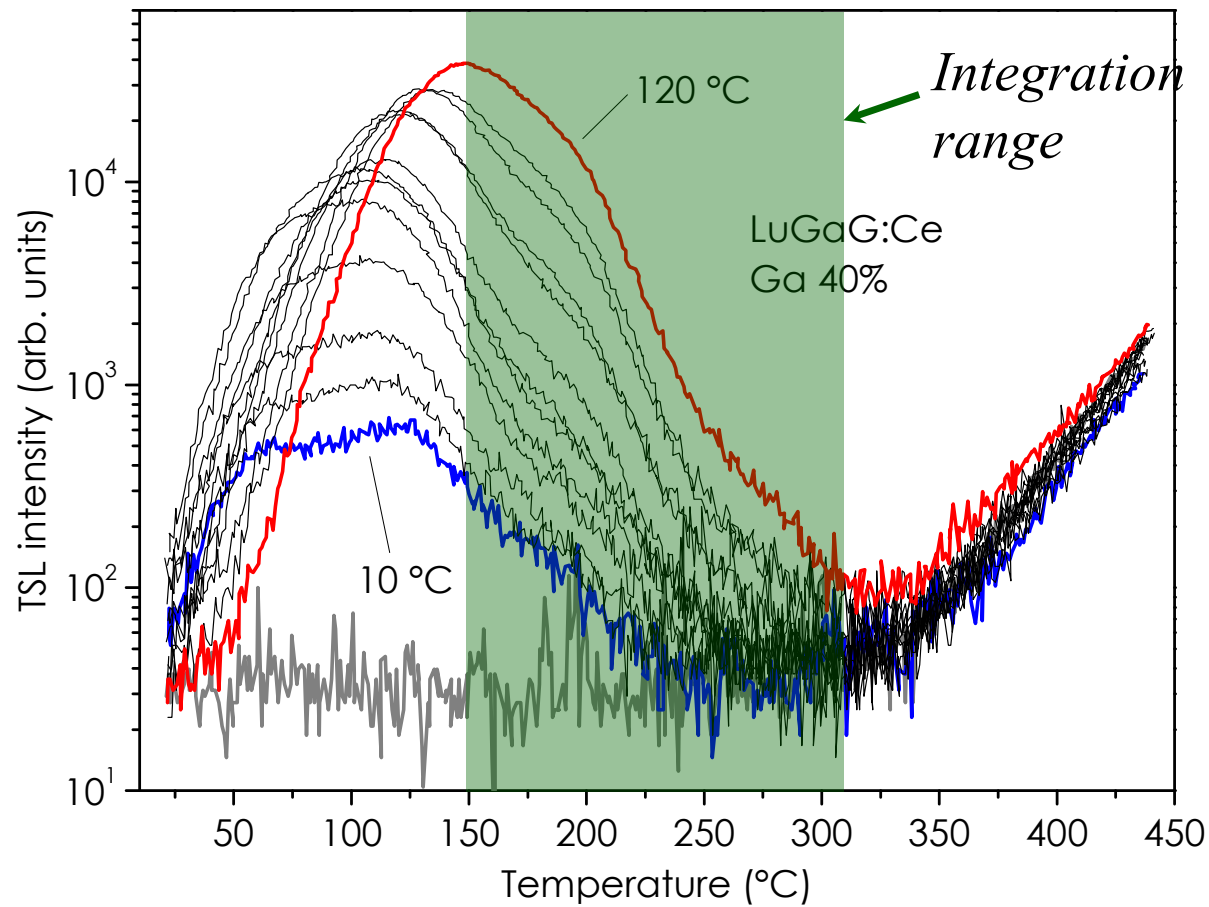
PLE

# TSL excitation spectrum (TSL intensity vs. excitation wavelength)



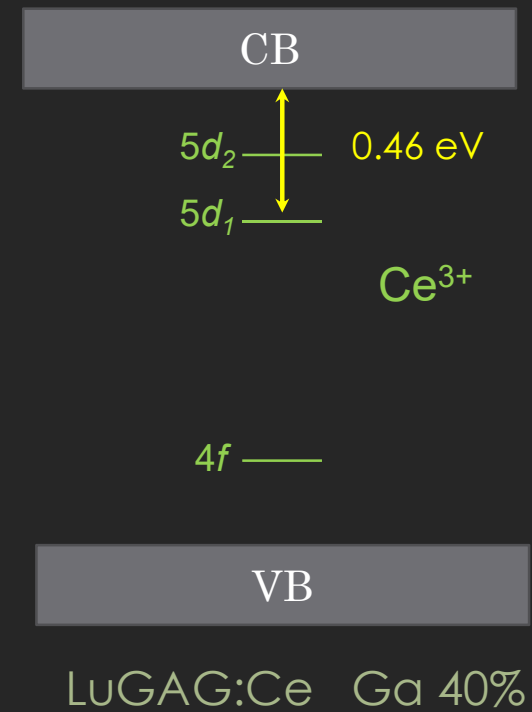
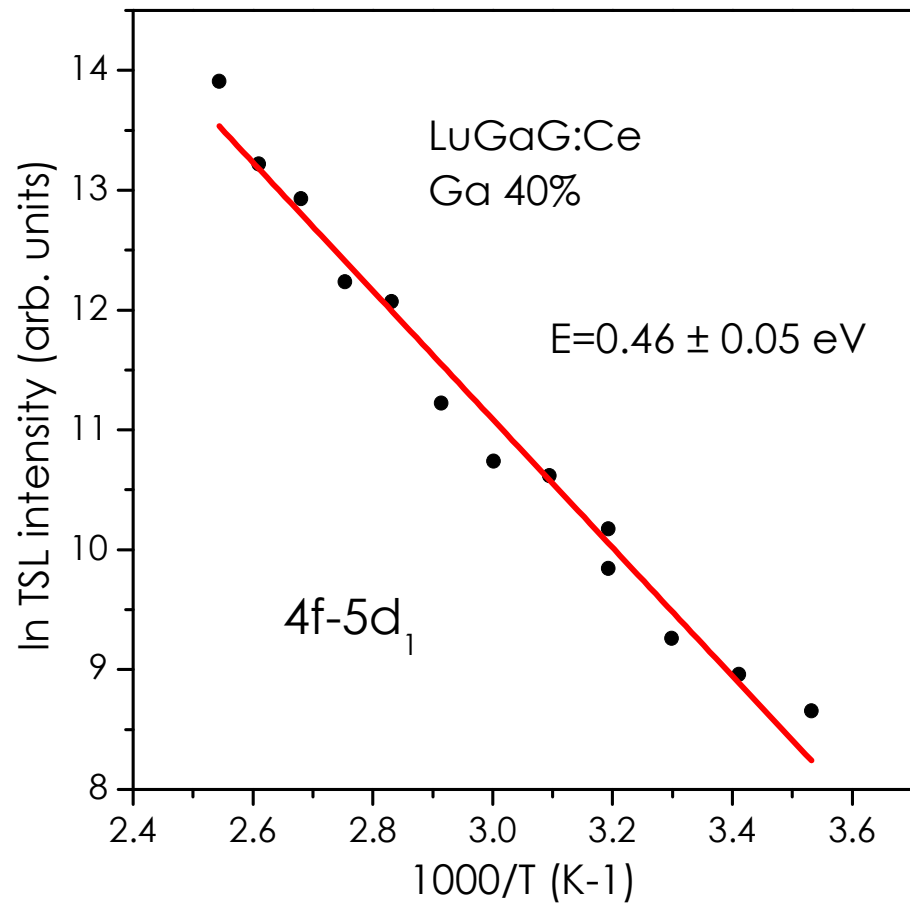
- It is extremely important to first verify the TSL excitation spectrum in order to check the ionization path of the trapped electrons.
- In LuGAG:Ce (Ga 20%), for example, exciting with 440 nm light the trapped electrons are nevertheless ionized via the 5d<sub>2</sub> Ce level.

# Glow curves: LuGAG:Ce Ga 40% ( $4f$ - $5d_1$ )

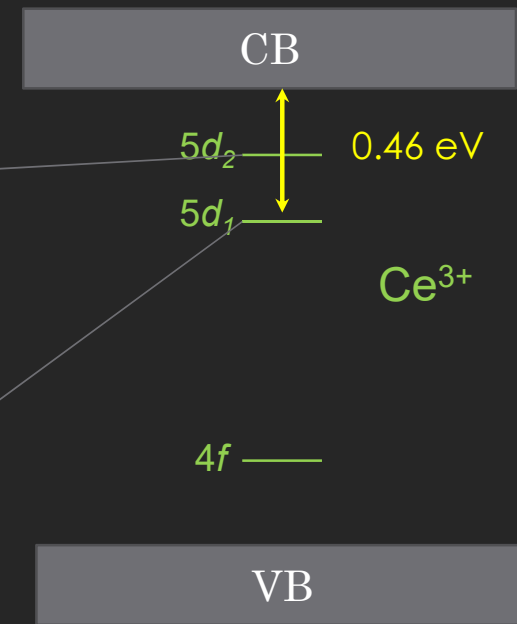
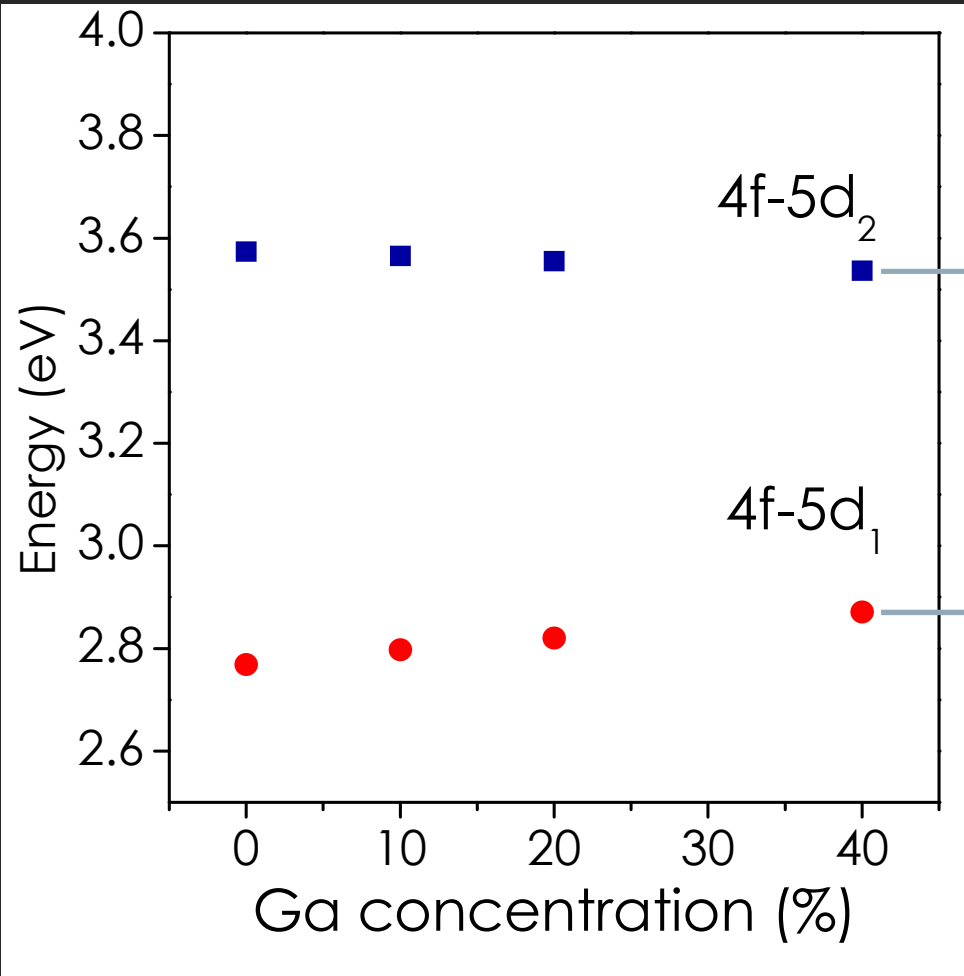


**LuGAG:Ce  
Ga 40%**

# Arrhenius plot: LuGAG:Ce Ga 40% ( $4f-5d_1$ )



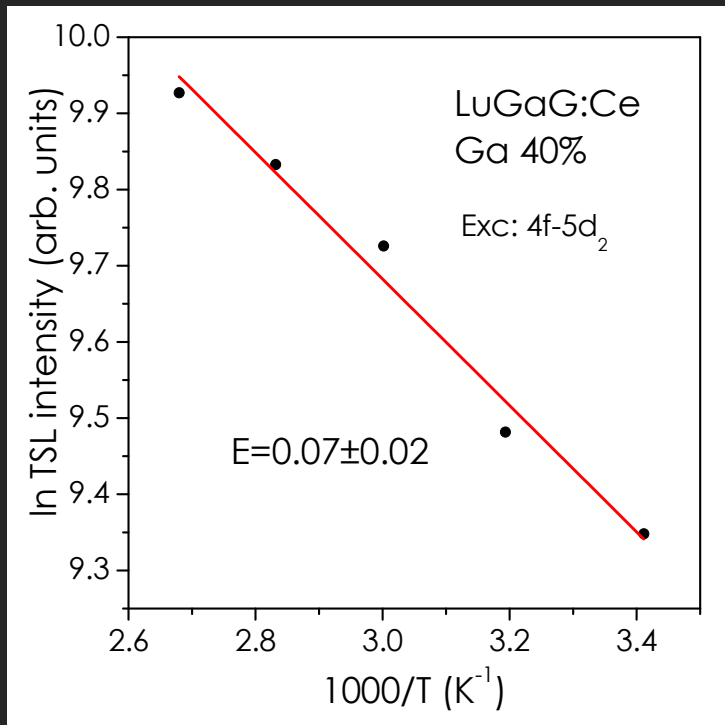
# Arrhenius plot: LuGAG:Ce Ga 40% ( $4f-5d_1$ )



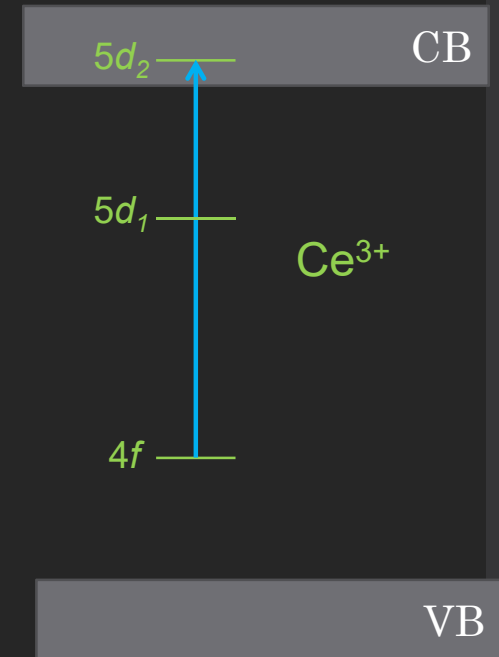
LuGAG:Ce Ga 40%

Level  $5d_2$  is inside the CB

# Ionization energy: LuGAG:Ce Ga 40% (4f-5d<sub>2</sub>)

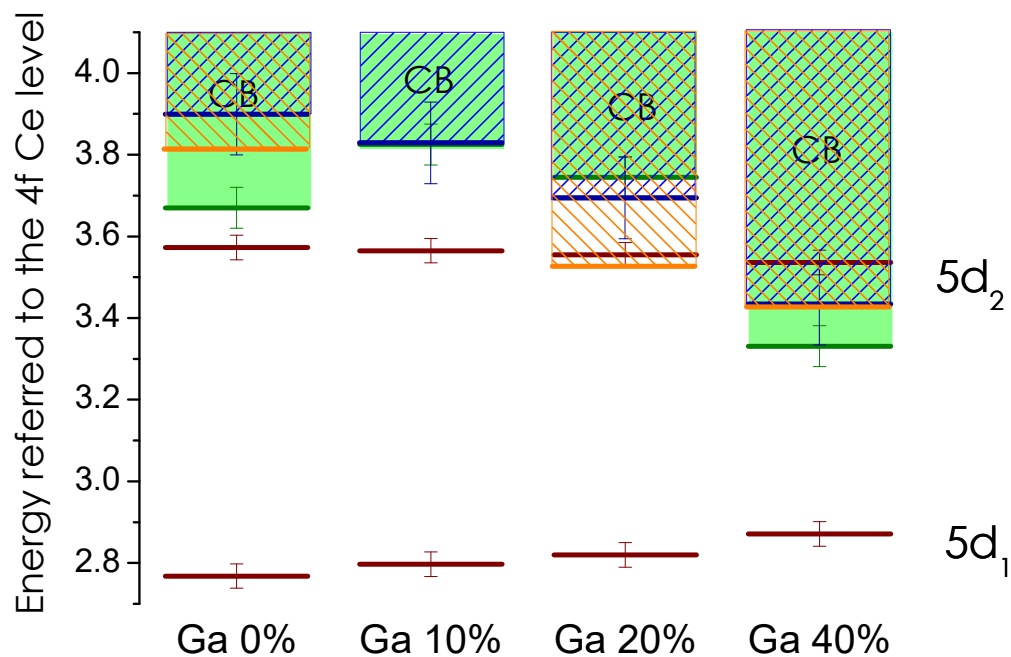


- **Despite** the 5d<sub>2</sub> Ce level in LuGAG:Ce Ga 40% lies **within th CB**, an **ionizaiton threshold** of about **0.07 eV** was evidenced.
- A similar energy (0.08 eV) was obtained by *van der Kolk et al.* for the 5d<sub>2</sub> Ce level in LSO:Ce and ascribed to the formation and subsequent dissociation of a Ce-bound exciton.
- Most of the vibrational lines in LuGAG Raman spectrum are in the 400-800 cm<sup>-1</sup> range (0.05-0.1 eV).



**LuGAG:Ce Ga 40%**

# Ce 5d level scheme in $\text{Lu}_3(\text{Ga}_x\text{Al}_{1-x})_5\text{O}_{12}$



Data obtained from:

- OA
  - Thermal ionization
  - Dorenbos
  - TSL
  - JSL
- J. Lumin. PRB (2011) (2012)*



# Conclusions

- The presence of defects can be exploited to obtain useful informations on the optical properties of luminescent materials
- Unconventional use of the TSL technique allowed to:
  - selectively evaluate delocalized band shift
  - localize the excited levels of a luminescence centre in the band gap